




CHILDREN'S EDUCATION SOCIETY (Regd.)  
**THE OXFORD COLLEGE OF ENGINEERING**  
(Recognised by the Govt. of Karnataka, Affiliated to Visvesvaraya Technological University, Belagavi.  
Approved by A.I.C.T.E. New Delhi.  
Recognised by UGC Under Section 2(f)  
Bommanahalli, Hosur Road, Bangalore - 560 068.  
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## Sample Course file & Mentor book

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**PRINCIPAL**  
The Oxford College of Engineering  
Bommanahalli, Hosur Road  
Bangalore-560 068



# THE OXFORD COLLEGE OF ENGINEERING

Hosur Road, Bommanahalli, Bengaluru-560 068

Website: [www.theoxford.edu](http://www.theoxford.edu) Email: [engprincipal@theoxford.edu](mailto:engprincipal@theoxford.edu)

(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU Belgaum)

## DEPARTMENT OF MECHATRONICS ENGINEERING

### COURSE FILE

Faculty Name	Mr. Dhananjaya V
Subject Name	Micro and Smart System Technology and Micro and Smart System Technology Lab
Subject Code	15MT54/15MTL58
Semester	V <sup>th</sup> Semester
Academic year	2018-19

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The Oxford College of Engineering  
Bommanahalli, Hosur Road  
Bengaluru-560 068

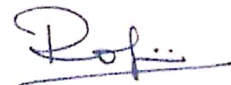




# MICRO & SMART SYSTEMS TECHNOLOGY (15MT54)

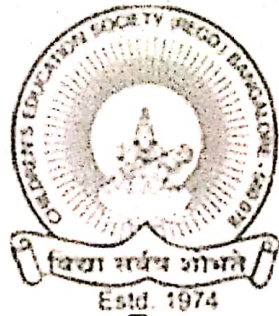
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HOD, MTE  
Prof. & HOD

Department of Mechatronics  
The Oxford College Of Engineering  
Bommanahalli, Bangalore - 560 086.



## **THE OXFORD COLLEGE OF ENGINEERING**

### **VISION OF THE INSTITUTE**

To be a respected and most sought after engineering educational institution engaged in equipping individuals to be capable of building learning organization in the new millennium.

### **MISSION OF THE INSTITUTE**

To develop competent students with good value systems to face challenges of the continuously changing world.

## DEPARTMENT OF MECHATRONICS ENGINEERING

### VISION

To develop the Mechatronics engineering department as a leading educational and research department with innovation in the design and development of electro-mechanical systems, intelligent machines and product.

## DEPARTMENT OF MECHATRONICS ENGINEERING

### MISSION

Mission of the Department	
M1	To provide an outstanding education in Mechatronics engineering with a rich diversity of skills
M2	To contribute to the community prosperity through professional services and research
M3	To prepare graduates with ability to engage in life long learning and capable of carrying out engineering practice with competence.

### PROGRAM EDUCATION OBJECTIVES (PEOS)

PEO 1:	Include knowledge of basic engineering sciences and fundamentals of mechanical, electrical and computer systems.
PEO 2:	Create ability in graduates to design, develop product and applications in the field of automation and Mechatronics and be able to use engineering tools that will enhance their productivity.
PEO 3:	Prepare graduates to be effective engineers with good analytical and problem solving skill to innovate, research and develop in a multidisciplinary Mechatronics environment.





CHILDREN'S EDUCATION SOCIETY (REGD.)

Administrative Office:

1<sup>st</sup> Phase JP Nagar, Bengaluru - 560 078

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## THE OXFORD COLLEGE OF ENGINEERING

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☎: 080-30219601/602/604/736, Fax: 080-25730551/30219629 Email: [engprincipal@theoxford.edu](mailto:engprincipal@theoxford.edu) Web: [www.theoxford.edu](http://www.theoxford.edu)

### TENTATIVE CALENDAR OF EVENTS FOR ODD SEMESTERS - 2018 - 19

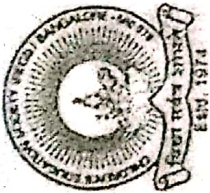
Week No.	Month	Day						No. of working days	Activities
		Mon	Tue	Wed	Thu	Fri	Sat		
1	Aug		-	01 FWD	02	03	04	4	1 <sup>st</sup> - First Working Day
2	Aug	06	07	08	09	10	11	6	
3	Aug	13	14	15 (H)	16	17	18	5	15 <sup>th</sup> - Independence Day
4	Aug	20	21	22 (H)	23	24	25	5	22 <sup>nd</sup> - Bakrid
5	Aug/Sep	27	28	29	30 T	31	1	6	
6	Sep	03 (T1)	04 (T1)	05 (T1)	06	07	08 (PTM)	6	03, 04 & 05 <sup>th</sup> - First Internal Assessment
7	Sep	10	11	12	13 (H)	14	15	5	13 <sup>th</sup> - Varasiddhi Vinayaka Vrata
8	Sep	17	18	19	20	21 (H)	22	5	21 <sup>st</sup> - Last day of Moharam
9	Sep	24	25	26	27	28	29	6	
10	Oct	01	02 (H)	03	04 T	05	06	5	2 <sup>nd</sup> - Gandhi Jayanthi
11	Oct	08 (H)	09	10	11	12	13	5	08 <sup>th</sup> - Mahalaya Amavasye
12	Oct	15 (T2)	16 (T2)	17 (T2)	18 (H)	19 (H)	20 (PTM)	4	15 <sup>th</sup> , 16 <sup>th</sup> & 17 <sup>th</sup> - Second Internal Assessment 18 <sup>th</sup> - Maha Navami Ayudapooja 19 <sup>th</sup> - Vijayadasami
13	Oct	22	23	24 (H)	25	26	27	5	24 <sup>th</sup> - Maharshi Valmiki Jayanthi
14	Oct / Nov	29	30	31	01 (H)	02	03	5	1 <sup>st</sup> - Kannada Rajyothsava
15	Nov	05	06 (H)	07	08 (H) T	09	10	4	06 <sup>th</sup> - Naraka Chaturdashi 08 <sup>th</sup> - Balipadyami Deepavali
16	Nov	12 (T3)	13 (T3)	14 (T3)	15	16	17 (PTM)	6	12, 13 & 14 - Third Internal Assessment
17	Nov	19	20 (LWD)	-	-	-	-	-	-----

Dr. R V Praveena Gowda  
Principal, TOCE

Dr. R V Praveena Gowda  
Principal

The Oxford College of Engineering  
Bommanahalli, Hosur Road





**THE OXFORD COLLEGE OF ENGINEERING**  
**HOSUR ROAD, BOMMANAHALLI, BENGALURU-560 068**  
**MECHATRONICS ENGINEERING DEPARTMENT**

TIME & DATE	9-9:55	9:55-10:50	11-11:55	11:55-12:50	1:30-2:25	2:25-3:20	3:20-4:15
MONDAY	THERMAL (15MT72)		THERMAL (15MT72)	MEMS (15MT54)			MST (17MT32)
TUESDAY		MEMS LABORATORY (15MTL58)				MST (17MT32)	
WEDNESDAY	MST (17MT32)		MEMS (15MT54)		THERMAL (15MT72)		
THURSDAY		MEMS LABORATORY (15MTL58)				MEMS (15MT54)	
FRIDAY		THERMAL (15MT72)		MST (17MT32)			
SATURDAY	MEMS (15MT54)						

FACULTY INCHARGE: DHANANJAYA . V

*[Signature]*  
 Faculty Sign

*[Signature]*  
 Signature of HOD  
 Department of Mechatronics  
 The Oxford College of Engineering  
 Bommanahalli, Bangalore 560 068







Course: B.E.			Sem: V Semester			Room No.: 603				
TIME DAY	9:00-9:55	9:55-10:50	11:00-11:55	11:55-12:50	L U N C H B R E A K			13:30-14:25	14:25-15:20	15:20-16:15
MON	DME (Chethan)	VI (Rajeshwari)	H & N (Murugan)	MEMS (Dhananjaya/Rajesh h B)				AIM (Murugan)	WNC (Aishwarya)	T/R/S
TUE	VI (Rajeshwari)	VI/MEMS lab (Rajeshwari/Dhananjaya)						T/R/S		
WED	H & N (Murugan)	DME (Chethan)	MEMS (Dhananjaya/Rajesh h B)	VI (Rajeshwari)				DME (Chethan)	AIM (Murugan)	
THU	AIM (Murugan)	VI/MEMS lab (Rajeshwari/Dhananjaya)						WNC (Aishwarya)	MEMS (Dhananjaya)	T/R/S
FRI	AIM (Murugan)	WNC (Aishwarya)	DME (Chethan)	WNC (Aishwarya)				T/R/S		
SAT	MEMS (Dhananjaya/Rajesh B)	H & N (Murugan)	VI (Rajeshwari)	H & N (Murugan)						
SUB. CODE		SUBJECT			NAME OF THE FACULTY					
15MT51		Design Of Machine Elements			Mr Chethan S					
15MT52		Virtual Instrumentation			Mrs Rajeshwari M					
15MT53		Hydraulics and Pneumatics			Mr Thirumurugan N					
15MT54		Micro and smart system technology			Mr Dhananjaya V/Rajesh B					
15MT551		Wireless Network communication			Mrs Rani Aishwaryan S N					
15MT562		Automation in Manufacturing			Mr Thirumurugan N					
15MTL57		Virtual Instrumentation Lab			Mr Rajeshwari M					
15MTL58		Micro and smart system technology Lab			Mr Dhananjaya V/Rajesh B					
CLASS TEACHER:		Mr Thirumurugan N			Engineering					

Time Table Coordinator

Chief Time Table Coordinator

Head of the Department

Principal

Professor, Anna University  
College of Engineering  
Chennai-600 068.



Course: B.E.

Sem: 3 - Semester

Room No.: 606

TIME DAY	9:00-9:55	9:55-10:50	11:00-11:55	11:55-12:50	13:30-14:25	14:25-15:20	15:20-16:15
MON	ADE (Dr.Rohini)/Rani TS	MT/ADE lab (Chethan S/Tulasi K L)			CS (Tulasi KL)	CO (Rajeshwari)	T/R/S
TUE	MOM (Chethan)	Maths-III (selestina)	ADE (Dr.Rohini)/Rani TS	MOM (Chethan)	CS (Tulasi KL)	MST (Dhananjaya)	T/R/S
WED	MST (Dhananjaya)	CO (Rajeshwari)	S B H R O E	Maths-III (selestina)	ADE (Dr.Rohini)/Rani TS		
THU	ADE (Dr.Rohini)/Rani TS	MOM (Chethan)	R A T K	Maths-III (selestina)	T/R/S		
FRI	CS (Tulasi KL)	CO (Rajeshwari)		MST (Dhananjaya)	MOM (Chethan)		
SAT	CO (Rajeshwari)	MT/ADE lab (Chethan S/Tulasi K L)					
SUB. CODE	SUBJECT			NAME OF THE FACULTY			
17MT31	Engineering Mathematics III			selestina			
17MT32	Material science and metallurgy			Mr Dhananjaya V			
17MT33	Mechanics of Materials			Mr Chethan S			
17MT34	Control System			Mrs Tulasi K L			
17MT35	Analog and Digital Electronics			Dr. Rohini Deshpande/Rani TS			
17MT36	Computer Organization			Mr Rajeshwari M			
17MTL37	Mechanical Lab- I			Mr Chethan S			
17MTL38	analog and Digital Electronics lab			Mr Tulasi K L			
CLASS TEACHER:	Ms Chethan S						

Time Table Coordinator

Head of the Department

Principal

Chief Time Table Coordinator  
The Oxford College of Engineering  
Bangalore-560066



**MICRO & SMART SYTEMS TECHNOLOGY**

[As per Choice Based Credit System (CBCS) scheme]

SEMESTER – V

Subject Code	15MT54	IA Marks	20
Number of Lecture Hours/Week	04	Exam Marks	80
Total Number of Lecture Hours	50	Exam Hours	03

CREDITS – 04

Course Objectives: Students will be able to

1. gain knowledge of Smart Materials, Sensors & Actuators, Microsystems.
2. understand the Operation of Smart Devices & Systems, Electronic Circuits & Control for MEMS, Methodology of Micro-manufacturing.

Modules	Hours Teaching	Revised Bloom's Taxonomy(RBT) Level
<b>Module -1</b>		
<b>Introduction to Micro and Smart systems:</b> Miniaturization, Microsystems versus MEMS, Micro-fabrication, Smart Materials, Structures & Systems, Integrated Microsystems ,Application of Smart Materials & Microsystems.	10 Hours	
<b>Module -2</b>		
<b>Micro and Smart Devices and Systems: Principles and Materials:</b> Definitions and salient features of sensors, actuators, and systems.Sensors: silicon capacitive accelerometer, piezoresistive pressure sensor, Portable blood analyzer, conductometric gas sensor. Actuators: Micromirror Array for Video Projection, Piezo-electric based inkjet print head,electrostatic comb-drive, Magnetic microrelay.	10 Hours	
<b>Module -3</b>		
<b>Micromachining Technologies:</b> Silicon as a Material for Micromachining, Silicon wafer preparation, thin-film deposition techniques, Lithography, Etching, Silicon micromachining:surface micromachining bulk micromachining. Specialized Materials for Microsystems.	10 Hours	
<b>Module -4</b>		
<b>Electronics Circuits for Micro and Smart Systems.</b> Semiconductor devices: Diode, Schottky diode,Tunnel diode,BJT ,MOSFET,CMOS circuits ,Electronics Amplifiers ,Op-Amp based circuits ,Practical Signal Conditioning Circuits for Microsystems. Circuits for Conditioning Sensed Signals.	10 Hours	

#### Module -5

**Implementation of Controllers for MEMS & Case Studies of Integrated Microsystems.** Design Methodology, PID controller, Circuit Implementation, Digital controller, Microcontroller & PLC. Case Studies of Integrated Microsystems: BEL pressure sensor, design considerations, performance parameters, practical implementations, design of electronics circuits, Integration of pressure Sensor and Smart Structure in vibration control.

10 Hours

Course Outcomes: On completion of the course the student will

1. have knowledge of Smart Materials, Sensors & Actuators ,Microsystems.
2. understand the Working Methodology of Smart Devices & Systems, Electronics Circuits & Control for MEMS, Methodology of Micro-manufacturing.

**Graduate Attributes (as per NBA):**

**Question paper pattern:**

- The question paper will have TEN questions.
- Each full question consists of 16 marks.
- There will be 2 full questions (with maximum of FOUR sub questions) from each module.
- Each full question will have sub questions covering all the topics under a module.
- The students will have to answer 5 full questions, selecting one full question from each module.

**Text Books :**

1. Micro and Smart Systems: G.K.Ananthasuresh, K.J.Vinoy, S.Gopalakrishnan, K.N.Bhat, V.K.Aatre, Wiley India 2010.

**Reference Books:**

1. Design and Development Methodologies, Smart Material Systems and MEMS: V. Varadan, K. J. Vinoy, S. Gopalakrishnan, Wiley.
2. MEMS- Nitaigour Premchand Mahalik, TMH 2007.
3. MEMS & Microsystems: Design and Manufacture, Tai-Ran Hsu, Tata Mc-Graw-Hill.



## LESSON PLAN (SUBJECT - 3)

Semester : V SEM

Subject with Code : 15 MT 54 (MEMS)

Week	Hour	Date	Topic to be covered
1			
2			
3	1	11/08/18	Introduction to micro and Smart S/m's,
	4	13/08/18	micro system, micro sensors and micro actuators
	6	16/08/18	miniaturization, uses, S
	1	18/08/18	Smart materials and systems.
4	4	20/08/18	Integrated micro-systems, multidisciplinary aspects, H/m
	6	23/08/18	Applications of Smart materials & M. systems or MEMS
	1	25/08/18	Micro & Smart devices, & features of Sensors, Actuators, S/m.
5	4	27/08/18	Sensors, and types of Sensors, 1. Silicon capacitive accel.
	3	29/08/18	Piezoresistive pressure sensor, portable blood analyser.
	6	30/08/18	Conductometric gas sensor.
	1	01/09/18	Actuator: types, 1. micro-mirror array for Video projection.
	6	06/09/18	Piezo - Electric based Inkjet head.
6			
	1	08/09/18	Electro - static comb drive, magnetic micro relay.
7	4	10/09/18	Silicon as a material for micro - machining.
	3	12/09/18	Silicon wafer preparation.
	1	15/09/18	thin film deposition technique.

# LESSON PLAN (SUBJECT - 3)

Semester : V SEM

Subject with Code : 15 MT 54 (MEMS)

Week	Hour	Date	Topic to be covered
8	4	17/09/18	Lithography process.
	3	19/09/18	Etching technique
	6	20/09/18	Silicon micro machining : surface & bulk micromachining
	1	22/09/18	Specialized materials for micro-systems.
9	4	24/09/18	Semi-conductor devices, Diode, Schottky diode...
	3	26/09/18	BJT
	6	27/09/18	MOSFET
	1	29/09/18	CMOS Circuits
10	4	01/10/18	Electronic Amplifiers
	3	03/10/18	Op-Amp based Circuits
	6	04/10/18	practical Signal Conditioning Circuits for M. Systems
	1	06/10/18	Circuits for Conditioning Sensor sensed Signals.
11			
	3	10/10/18	Design methodology
	6	11/10/18	PID Controller
	1	13/10/18	Circuit Implementation
12			
	1	20/10/18	Digital Controller
13	4	22/10/18	Micro-controller & PLC
	6	25/10/18	Case studies of Integrated BiMsm: BEL pressure sensor
	1	27/10/18	Design Considerations, performance parameters.
14	4	29/10/18	practical implementations,
	3	31/10/18	Design of Electronic Circuits
	1	03/11/18	Integration of pressure sensor & smart structure in vibration control.

FACULTY INCHARGE

Prof. [Signature]  
HOD, MTE





# THE OXFORD COLLEGE OF ENGINEERING

Hosur Road, Bommanahalli, Bengaluru-560 068

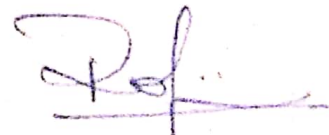
Website: [www.theoxford.edu](http://www.theoxford.edu) Email : [engprincipal@theoxford.edu](mailto:engprincipal@theoxford.edu)

## DEPARTMENT OF MECHATRONICS ENGINEERING

### LIST OF 3<sup>RD</sup> MECHATRONICS ENGINEERING STUDENTS

Sl No	USN	STUDENTS NAME
1	1OX17MT002	AHMED ADEEL GAZALI
2	1OX17MT004	AKSHAY KUMAR REDDY
3	1OX17MT007	AMAN RAJ
4	1OX17MT008	ANNIESH D K
5	1OX17MT009	BHARATH KUMAR L
6	1OX17MT010	BRUNDHA J
7	1OX17MT011	CHETHAN M
8	1OX17MT012	DARSHAN K N
9	1OX17MT013	DEEKSHITH G S
10	1OX17MT014	DESHNA MOHANTY
11	1OX17MT016	JEEVITH R
12	1OX17MT017	K VISHNU
13	1OX17MT018	KIRAN S
14	1OX17MT019	KISHORE S
15	1OX17MT020	MANISH CHANDRA V
16	1OX17MT022	MONICA P
17	1OX17MT023	MONISH PRAKASH A
18	1OX17MT024	MUNNAKUMAR PANDIT
19	1OX17MT025	MURULI KRISHNA N
20	1OX17MT027	NIKHIL SRINIVAS K R
21	1OX17MT028	SAM CHRISTOPHER P
22	1OX17MT031	RASHMI R
23	1OX17MT032	SANJAY J
24	1OX17MT033	SANJAY R
25	1OX17MT034	SHREESHA N BHAT
26	1OX17MT035	SHREYA BIRADAR G
27	1OX17MT038	UDAY KUMAR K
28	1OX17MT039	VARSHADHARE K
29	1OX17MT040	VARUN

30	IOX17MT041	VIJAY D
31	IOX17MT042	VIJAYALAKSHMI S
32	IOX17MT043	VINAY KUMAR T V
33	IOX17MT044	VISHAL B S
34	IOX17MT045	VISHNU MANOHAR TUMSI S
35	IOX17MT046	VISHNU S KUMAR
36	IOX16MT022	MANJUNATH PRABHU M R
37	IOX16MT003	AKANKSHA V REDDY
38	IOX18MT400	BHARATH N
39	IOX18MT401	BHARGAV B S
40	IOX18MT402	DIXIT H M
41	IOX18MT403	HEMANTH REDDY
42	IOX18MT404	JEEVA A
43	IOX18MT405	MOHAN BABU M
44	IOX18MT406	MOHAN KUMAR S
45	IOX18MT407	NIRANJAN S
46	IOX18MT408	OMKAR ZADAGE
47	IOX18MT409	PRAVEEN S SALIMATH
48	IOX18MT410	RASHISH KUMAR
49	IOX18MT411	THRILOK V
50	IOX18MT412	ZAHID AHMED



**HOD, MTE**  
**Prof. & HOD**

Department of Mechatronics  
The Oxford College of Engineering  
Bommanahalli, Bangalore 560 088





# THE OXFORD COLLEGE OF ENGINEERING

DEPARTMENT OF MECHATRONICS ENGINEERING

Hosur Road, Bommanahalli, Bengaluru-560 068

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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU Beigaluru)

Academic Year: AUG 18-DEC 18

INTERNAL TEST – I(CBCS Scheme)

SUB CODE: 15MT54

SUB NAME: Micro and Smart System Technology

SEM: V

DATE: 04.09.2018

MAX MARK: 40M

DURATION: 1Hr 30Mins

Answer any one full questions from each Part		5x6 =30marks	
Q. No.	<u>Part 1</u>	Marks	COs,POs
Q1.	What are smart systems? Explain the components of a smart system with the help of a block diagram.	08	CO1,PO1
Q2.	OR What are micro systems? Explain components of micro system? And mention the applications of micro system.	08	CO1,PO1
<u>Part 2</u>			
Q3.	What is miniaturization? Mention the need and advantages of miniaturization of systems.	08	CO2,PO1
Q4.	OR Elucidate the multidisciplinary aspects of Microsystems with the help of block diagram.	08	CO3,PO1
<u>Part 3</u>			
Q5.	Explain micro system as micro sensor and micro actuator with block diagram.	08	CO3,PO1
Q6.	OR What are smart materials? Different types of smart materials and explain working of any two smart materials.	08	CO4,PO1
<u>Part 4</u>			

Q7.	Explain sensors, actuators and systems. And write the characteristic features.  OR	08	CO6,PO1  CO5,PO1
Q8.	Explain the working principle of silicon capacitive accelerometer with the diagram.	08	

Part 5


Q.9.	Explain the working principle of piezo-resistive pressure sensor with block diagram..  OR	08	CO5,PO1  CO5,PO1
Q.10.	With the neat sketch explain the working of conductometric gas sensor.	08	

**Course Outcomes**

Students will be able to

1.	Know the basic concept of micro and smart system technology.
2.	Understand the need of micro size machines and devices.
3.	Know how this micro system technology is evolved in all fields of science and technology
4.	Know the smart materials and their characteristics for the smart system applications.
5.	Understand the working of different sensors for smart system applications.
6.	Know how the different components of smart systems are integrated with each other.

  
Faculty Signature

  
HOD Signature  
Prof. & HOD





THE OXFORD COLLEGE OF ENGINEERING  
DEPARTMENT OF MECHATRONICS ENGINEERING

Hosur Road, Bommanahalli, Bengaluru-560 068

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AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU, Belgaum

Academic Year: AUG'18 - DEC'18

SCHEME & SOLUTIONS  
INTERNAL TEST - I (CBCS Scheme)

SUB CODE: 15MT54

SUB NAME: MICRO & SMART SYSTEM TECHNOLOGY

SEM: V

DATE: 4-09-2018

MAX MARK: 40M

DURATION: 1Hr 30Mins

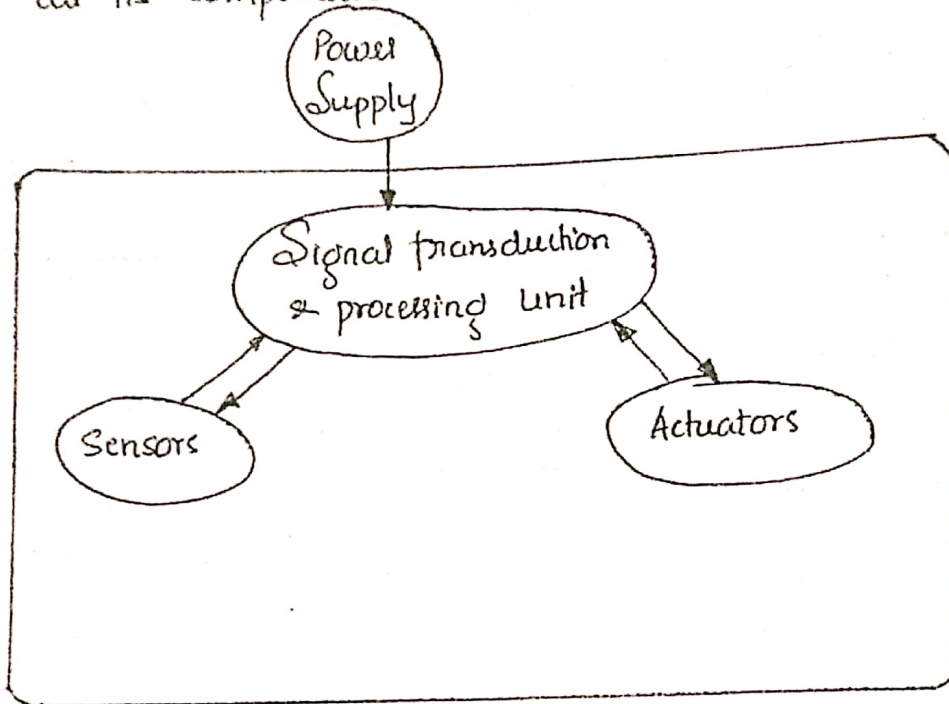
Q. No	Marks
PART - 1	
Q.1	8M
<p>Smart system:— smart system is system which integrates the properties of embedded sensors, actuators and controlled mechanisms in order to respond to a given stimulus in a functionally useful manner. This involves implementing of both hardware and software control mechanisms.</p> <p>— 2M</p> <p>schematic diagram of a smart system</p> <pre>graph TD     Structure[Structure] -- Force --&gt; Structure     Structure -- Strains --&gt; Sensor[Sensor]     Sensor -- "Electrical Signals" --&gt; Controller[Controller]     Controller --&gt; Actuator[Actuator]     Actuator --&gt; Structure</pre> <p>— 2M</p> <p>Explanation of working or Function of each component</p> <ol style="list-style-type: none"><li>Structure</li><li>Sensor</li><li>Controller</li><li>Actuator</li><li>Data base</li></ol> <p>— 4M</p>	

Q. No

Q2

MICRO SYSTEMS:

Explanation and definition of the micro system. 2M  
 Schematic diagram of micro system. and explaining all its components.



4M

8M

Applications of microsystems (minimum 4 applications). 2M

PART- 2

Q3

Miniaturization:

Explanation of miniaturization. -- 2M

Requirement or need of miniaturization -- 4M

Example of miniaturization -- 2M.

8M

Q4

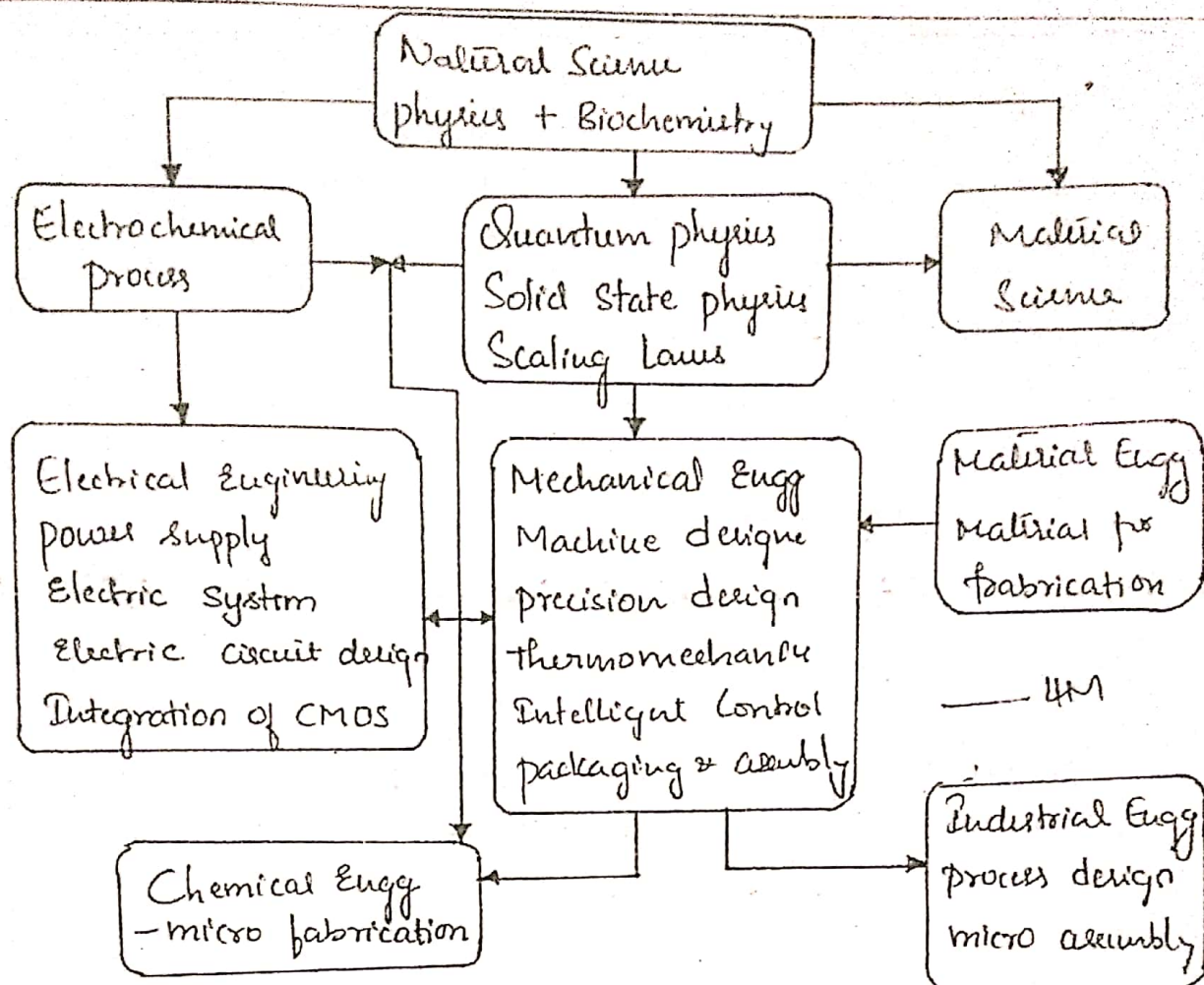
Multidisciplinary aspects of microsystems

Schematic diagram of multidisciplinary aspects.



Q. No

Marks



9M

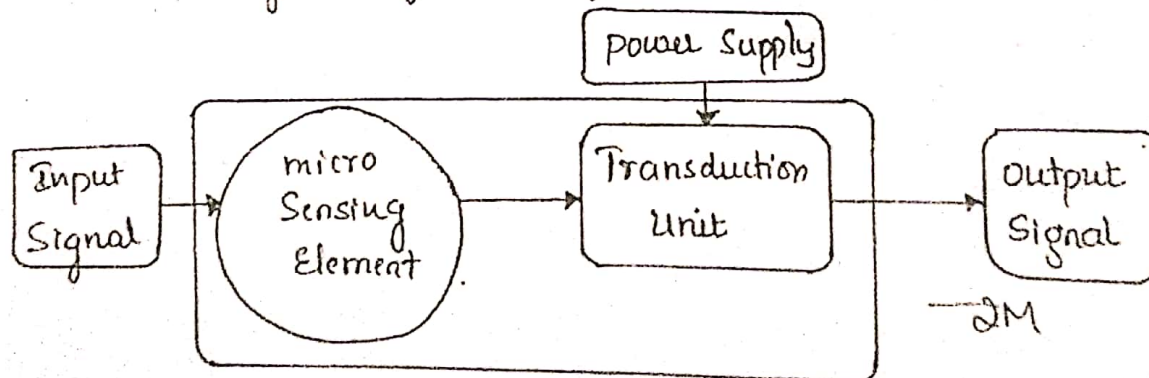
Explanation of all different Science and Engineering aspects of microsystems and their applications. — 4M

## PART - 3

Q.5.

Micro system as micro sensor

Schematic diagram of microsystem as micro sensor



— 2M

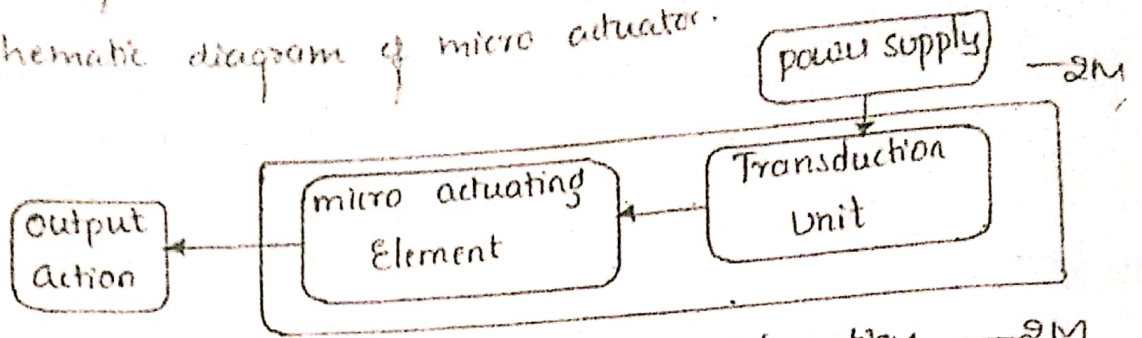
Explanation of Each Component — 2M



Q. No

Mark

Microsystem as micro actuator  
Schematic diagram of micro actuator.



Explanation of all components and function — 2M

Q6

Smart Materials :-

Smart materials definition and Explanation. — 2M

Different types of smart materials (6 types) — 2M

Explanation of any two types of smart materials — 4M

PART — 4

Q7.

Sensors  
actuators  
Systems } Definition — 3M

Salient feature of sensors: Accuracy, precision, Resolution, Repeatability, reproducibility.

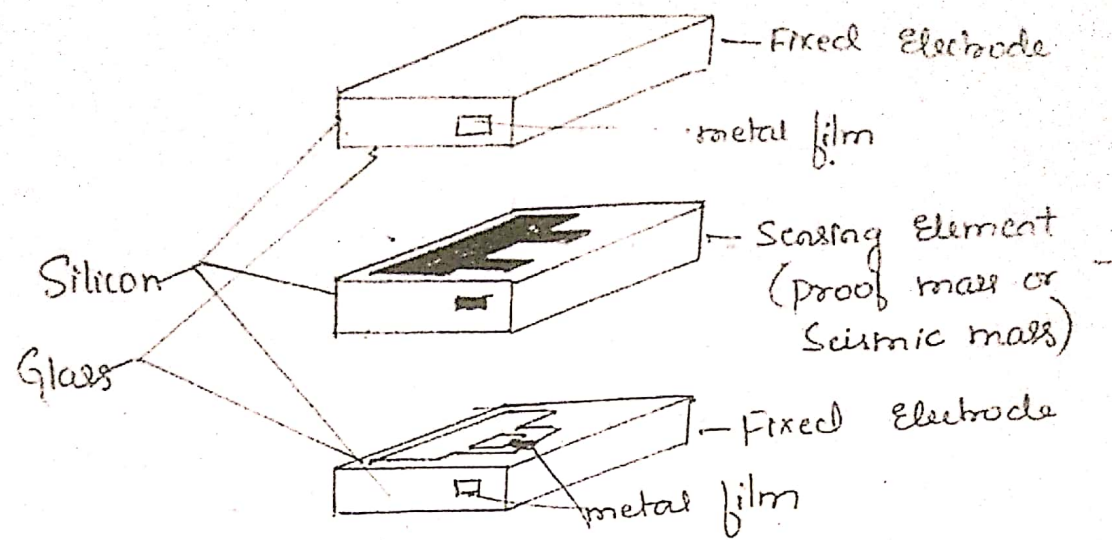
Salient feature of actuators: stress, Strain, max actuation stress, & Max actuation strain. } 5M

Systems feature any 3 points

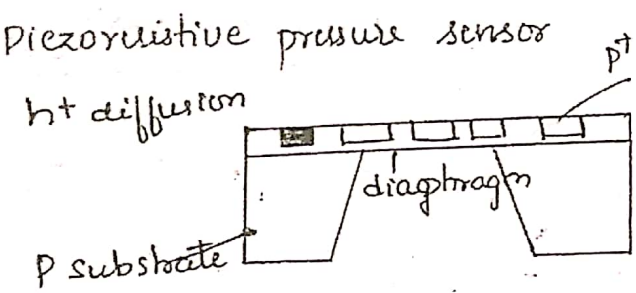
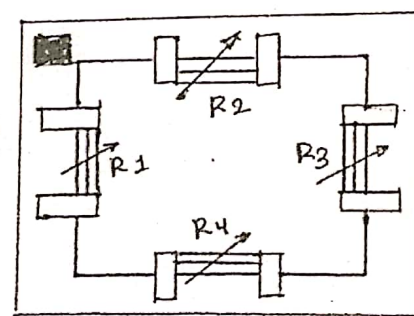
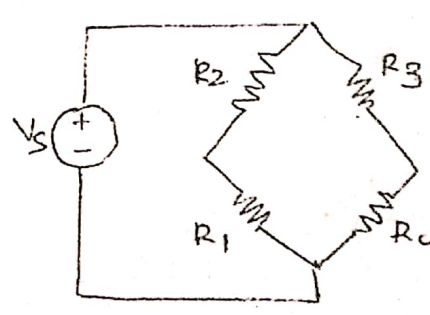
Q8.

Silicon Capacitive accelerometer

Schematic diagram of Silicon Capacitive accelerometer.

Q. No		Marks
	 <p>Diagram illustrating the structure of a Silicon Capacitive Accelerometer. The structure consists of three main layers: a top Fixed Electrode, a middle Sealing Element (proof mass or seismic mass), and a bottom Fixed Electrode. The layers are labeled with Silicon, Glass, and metal film. The diagram shows the internal structure of the device, including the proof mass and the electrodes.</p> <p>Explanation of working of Silicon Capacitive accelerometer — 5M</p>	8M

### PART - 5

Q. 9.	<p>Piezoresistive pressure sensor</p>    <p>Schematic diagram of piezoresistive pressure sensor — 3M</p> <p>Explanation of working of the above Sensor — 5M</p>	3M
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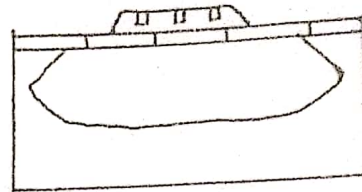
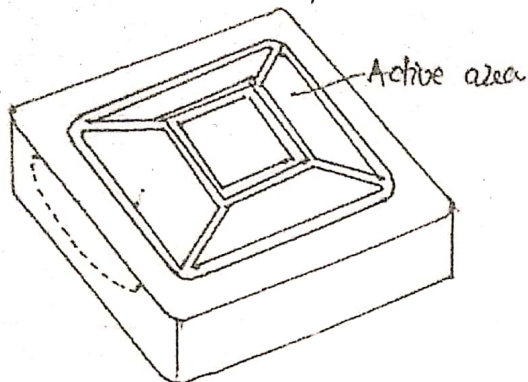
Q. No.

Marks

Q.10.

Conductometric Gas sensor

Schematic diagram of Conductometric Gas sensor



-3M

-3M

Explanation of working of Conductometric Gas sensor - 6M



# THE OXFORD COLLEGE OF ENGINEERING

DEPARTMENT OF MECHATRONICS ENGINEERING

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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU Belgaum)

Academic Year: AUG 18-DEC 18

INTERNAL TEST -II(CBCS Scheme)

SUB CODE: 15MT54

SUB NAME: MICRO & SMART SYSTEM TECHNOLOGY

SEM: V

DATE: 16.10.2018

MAX MARK: 40M

DURATION: 1Hr 30Mins

Answer any one full questions from each Part			5x6 =30marks
Q. No.	Part 1	Marks	COs,POs
Q1.	Explain the working principle of Piezo-electric based inkjet print head.	08	CO1,PO1
Q2.	OR With the neat sketch explain electrostatic comb drive.	08	CO1,PO1
Part 2			
Q3.	Explain the working principle of magnetic micro relay.	08	CO1,PO1
Q4.	OR With neat sketch explain silicon wafer preparation.	08	CO2,PO1
Part 3			
Q5.	With neat sketch explain thermal oxidation for silicon dioxide.	08	CO2,PO1
Q6.	OR Discuss the process of preparation of silicon dioxide, silicon nitride, polysilicon using chemical vapor deposition.	08	CO2,PO1
Part 4			



Q7.	With the necessary sketches, explain the key processes involved in photolithography. <b>OR</b>	08	CO3,PO1
Q8.	Explain surface micromachining to realize a cantilever structure with neat pictorial representations.	08	CO4,PO1


**Part 5**


Q.9.	With the help of neat sketch explain various steps involved in liftoff technique. <b>OR</b>	08	CO5,PO1
Q.10.	What is etching process and Explain (i) Dry etching (ii) Wet etching (iii) Isotropic etching	08	CO6,PO1

**Course Outcomes**

Students will be able to

1.	Know different types of actuators in the applications of microstructures.
2.	Know the materials which are used in fabrication of Microsystems.
3.	Understand the processes for the manufacturing of Microsystems active parts.
4.	Know the processes involved in the surface micromachining.
5.	Understand the manufacturing of the thin film.
6.	Know how the base structures in the Microsystems are produced by micromachining.

  
Faculty Signature

  
HOD Signature



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Academic Year: AUG'18 - DEC'18

SCHEME & SOLUTIONS  
INTERNAL TEST - II (CBCS Scheme)

SUB CODE: 15MT54

SUB NAME: MICRO & SMART SYSTEM TECHNOLOGY

SEM: V

DATE: 16.10.2018

MAX MARK: 40M

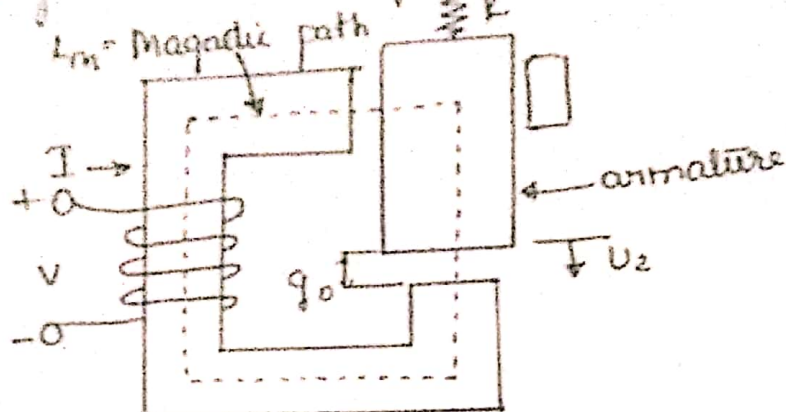
DURATION: 1 Hr 30 mins

Q. No		Marks
Q1.	<p>Part - 1</p> <p>Piezo - electric based Inkjet print head</p> <p>Schematic diagram of piezo - electric based inkjet print head. — 3M</p> <p>Explanation of working of piezo electric Inkjet print head. — 5M</p>	8M
Q2	<p>Electrostatic Comb drive</p> <p>Schematic diagram of Electrostatic Comb drive — 3M</p> <p>Explanation of working of Electrostatic comb drive — 5M</p>	8M



63

Magnetic micro relay



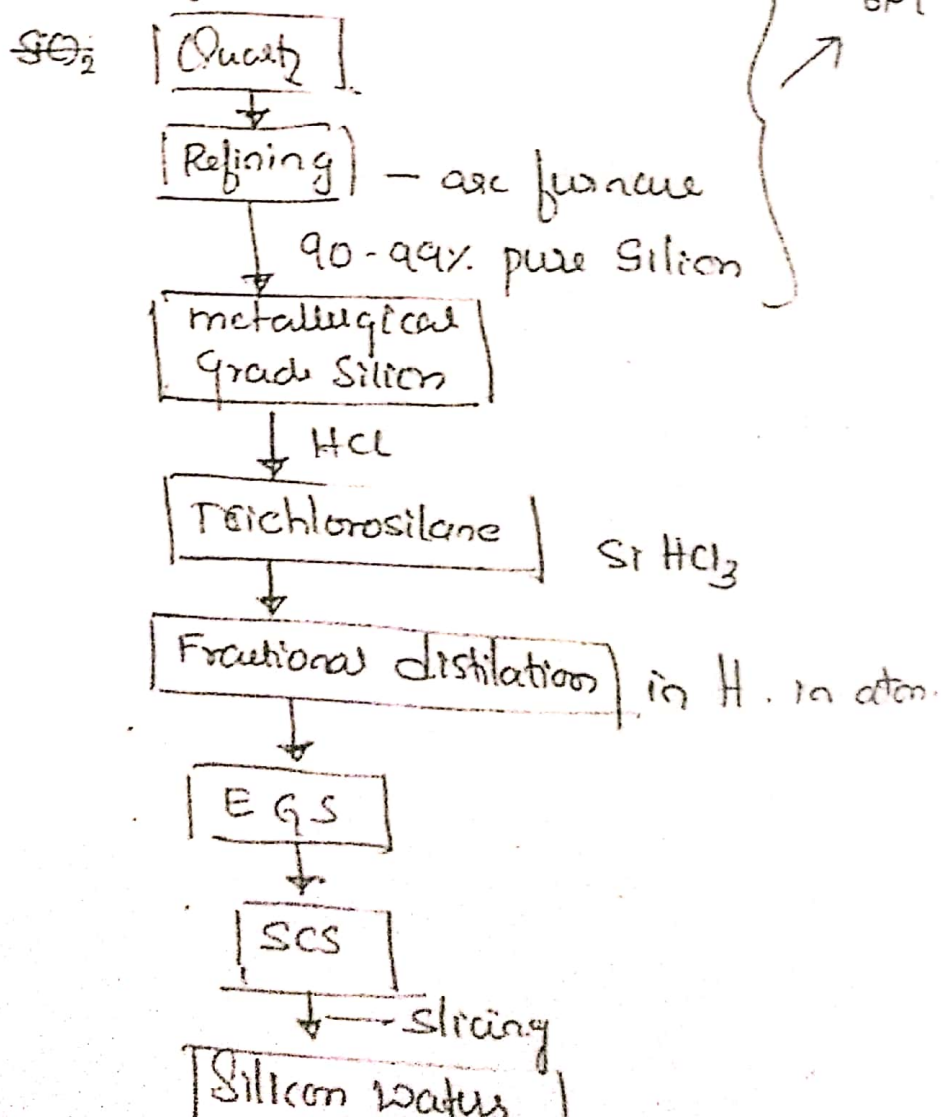
Schematic diagram of magnetic micro relay - 2M

Explanation of magnetic micro relay - 6M

64

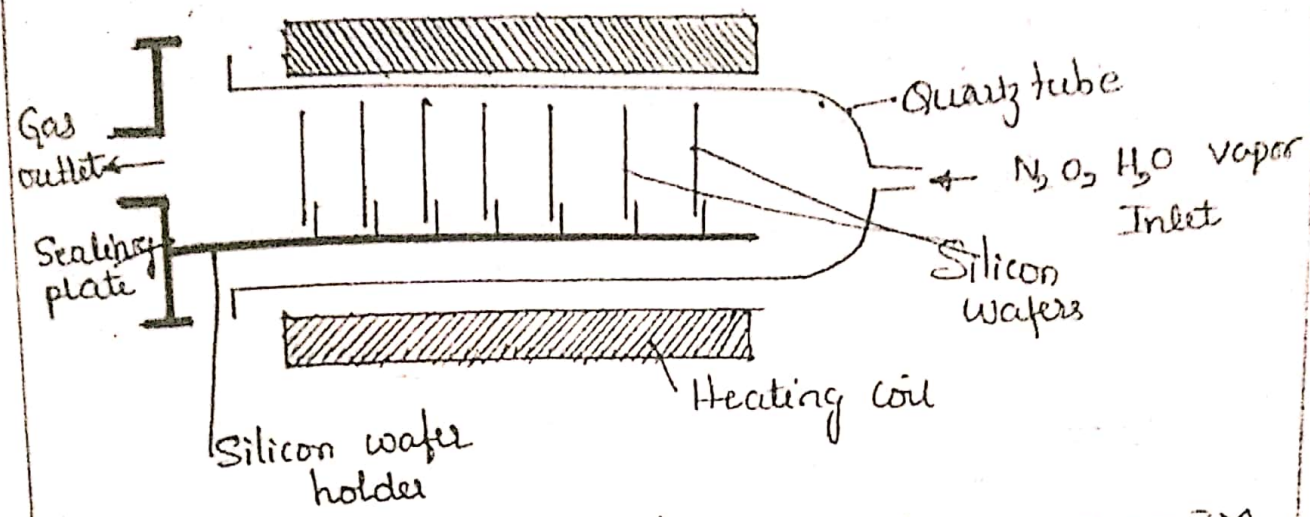
Silicon wafer preparation.

Explanation of Silicon as wafer material - 2M

Working  $\odot$  preparation flow diagram with explanation

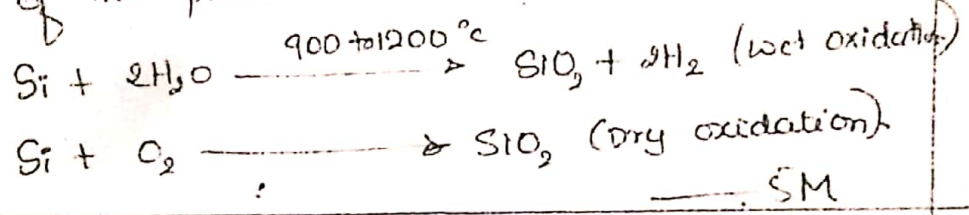
PART- 3

Thermal oxidation for Silicon dioxide



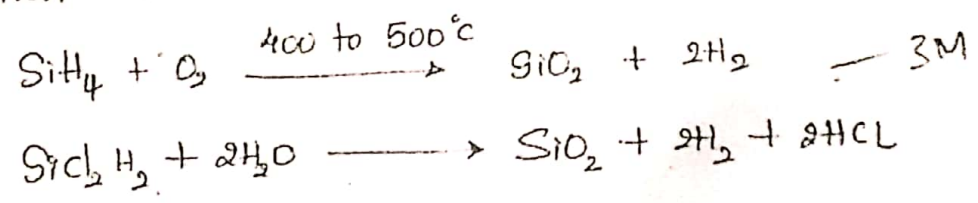
Schematic diagram of Thermal oxidation process — 3M

Explanation of the process with chemical reactions involved



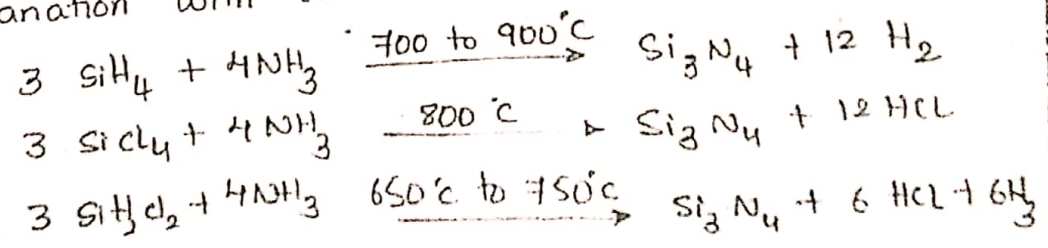
Silicon dioxide preparation

Explanation with chemical reactions involved.



Silicon nitride preparation

Explanation with chemical reactions involved

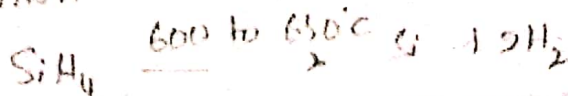




Q. No

Physical preparation using chemical vapor deposition

Explanation with chemical reactions

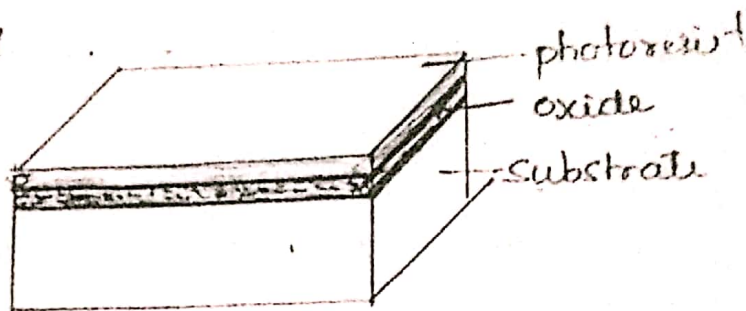


PART - 4

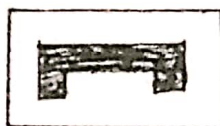
Q.3

# PHOTOLITHOGRAPHY

Start wafer with oxide thin film (a) resist coated on it

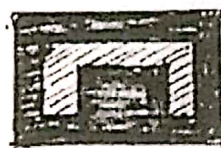
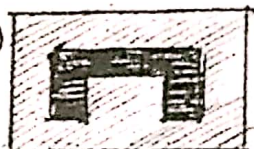


mask plate with image (b)



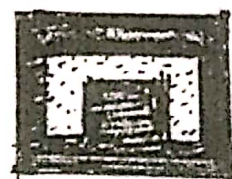
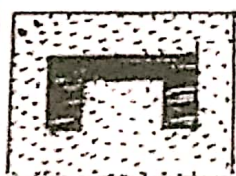
— mask plate pattern

after exposure (c)

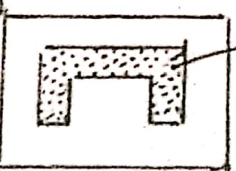


4M

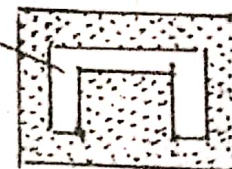
After developing (d)



After removal (stripping of resist) (e)



Transformed pattern on plate



Explanation of working in photolithography with steps involved

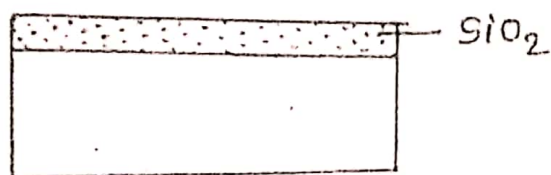
1. Resist Coating
2. Prebaking
3. UV exposure
4. Developing
5. Postbaking
6. Etching
7. photoresist Stripping

4M

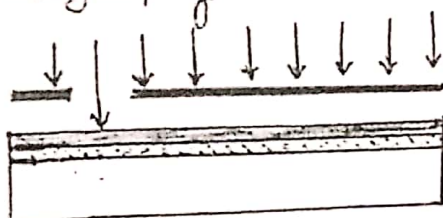
Surface micromachining to realize a Cantilever Structure

Set pictorial representation of surface micromachining to realize Cantilever Structure.

(a) deposit  $\text{SiO}_2$  on Si wafer



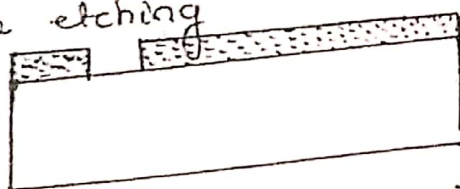
(b) UV Lithography



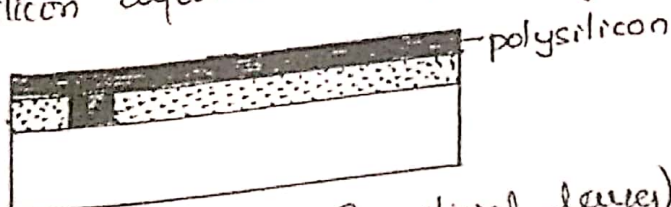
(c) Developing



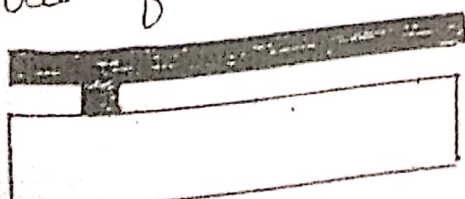
(d) Oxide etching



(e) polysilicon deposition and patterning



(f) removal of oxide (sacrificial layer)



Explanation of each steps in surface micromachining 4M

8M

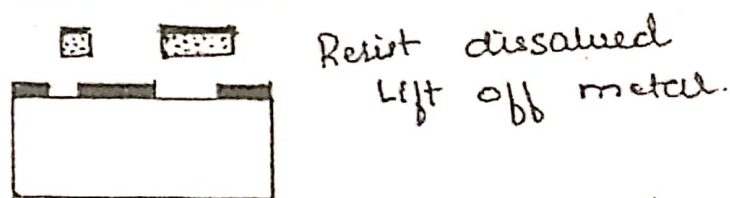
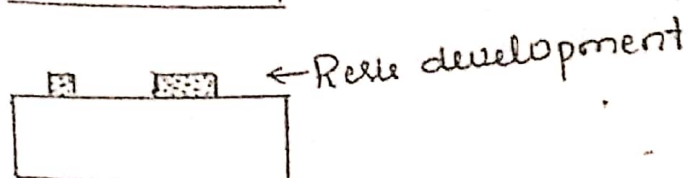
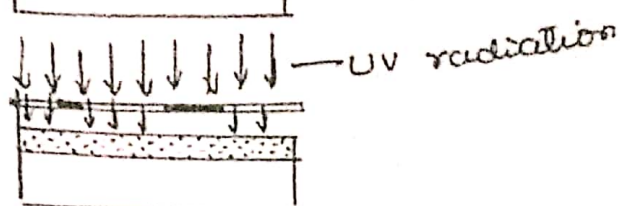
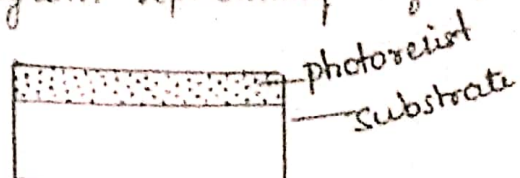


## PART 5

Q.4

LIFT OFF TECHNIQUE

Schematic diagram representing lift off technique. Steps



Explanation of lift off technique with each steps — 5M

Q.10.

Etching process :- explanation of etching process — 2M  
diff types of Etching process

i) Dry etching process — explanation — 2M

ii) Wet etching process — explanation — 2M

iii) Isotropic etching process — explanation — 2M.



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Academic Year: AUG 18-DEC 18

INTERNAL TEST – III (CBCS Scheme)

SUB CODE: 15MT54

SUB NAME: MICRO & SMART SYSTEM TECHNOLOGY

SEM: V

DATE: 23.11.2018

MAX MARK: 40M

DURATION: 1Hr 30Mins

Answer any one full questions from each Part			5x6 =30marks
Q. No.	Part 1	Marks	COs, POs
Q1.	With the neat sketch explain enhanced MOSFET with VI characteristics.	08	CO1,PO1
Q2.	OR Briefly explain the different OP-Amp based circuits.	08	CO1,PO1
Part 2			
Q3.	Explain the vibration control of beams in micro systems using neat sketch.	08	CO1,PO1
Q4.	OR Define Bulk micro machining. With the flow chart explain it.	08	CO2,PO1
Part 3			
Q5.	Explain the VI characteristics of BJT along with construction.	08	CO4,PO1
Q6.	OR Explain instrumentation Amplifier as a differential voltage amplifier.	08	CO3,PO1
Part 4			
Q7.	Explain Analog to Digital converter.	08	CO3,PO1
Q8.	OR Explain phase-locked loop, with a neat block diagram.	08	CO3,PO1
Part 5			




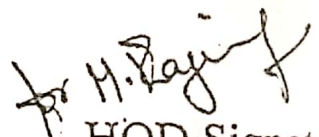
Q.9.	Reliability and key failure mechanisms in Microsystems.	08	CO5,PO1
Q.10.	OR Elucidate the characteristics and performance parameters of pressure sensor.	08	CO6,PO1

#### Course Outcomes

Students will be able to

1.	Understand the electronic circuits and control of MEMS
2.	Understand the working methodology of micro-machining.
3.	Understand the different circuits to control the micro systems.
4.	Know the different electronics devices to control MEMS.
5.	Understand drawbacks of micro systems by thier failure mechanisms.
6.	Know the characteristics & performance parameters of pressure sensors.

  
Faculty Signature

  
HOD Signature



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Academic Year: AUG'18 - DEC'18

SCHEME & SOLUTIONS

INTERNAL TEST - II (CBCS Scheme)

SUB CODE: 15MT54

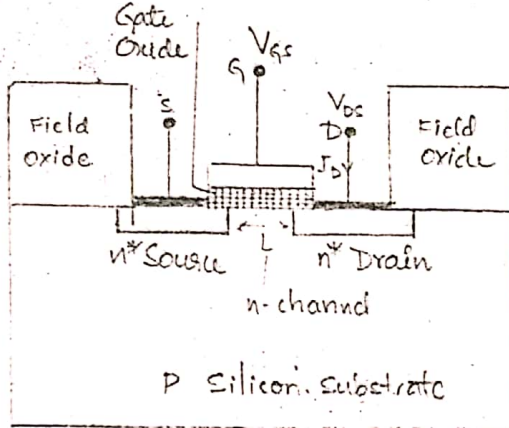
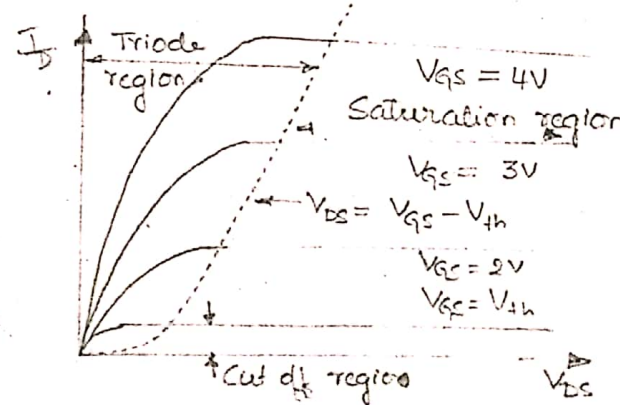
SUB NAME: MICRO & SMART SYSTEM TECHNOLOGY

SEM: V

DATE: 23-11-2018

MAX MARK: 40M

DURATION: 1Hr 30 Min

Q. No		Marks
Q1.	<p style="text-align: center;"><u>PART - 1</u></p> <p>MOSFET with VI characteristic</p>   <p style="text-align: right;">8M</p>	

Schematic diagram of n-channel MOSFET

Explanation of MOSFET with its different parameters and types of MOSFET and its operation.

VI characteristic of MOSFET :-

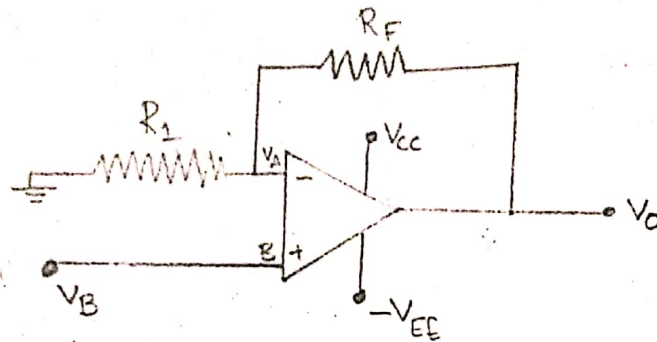
- i) Cut-off Region
- ii) Triode Region
- iii) Saturation region.



Q<sub>2</sub> OP-Amp based Circuits

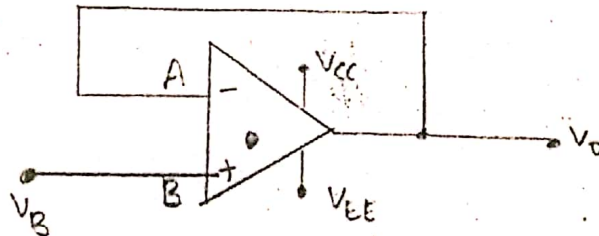
Explanation of different types of OP-Amp based Circuits

(i) Non-Inverting amplifiers

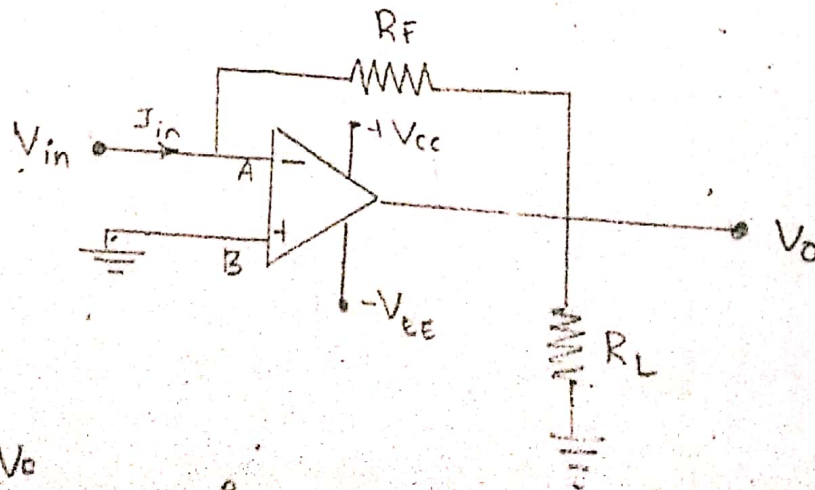


$$\frac{V_O}{V_{in}} = \frac{R_1 + R_F}{R_1} = 1 + \frac{R_F}{R_1}$$

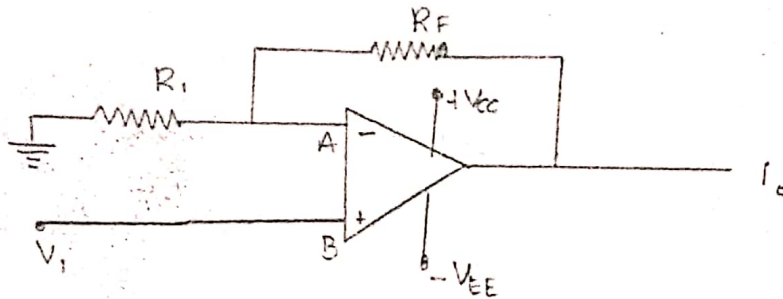
(ii) Voltage-follower



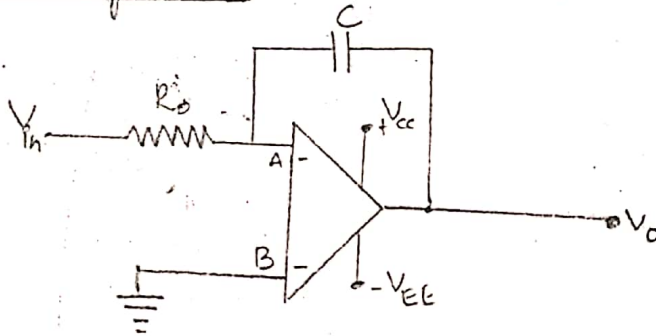
(iii) Transimpedance amplifier



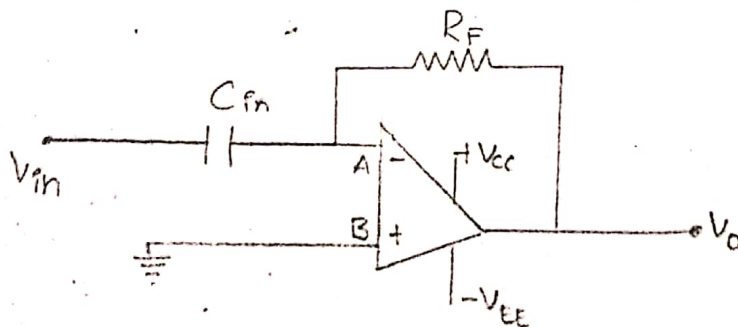
$$\frac{V_O}{V_{in}} = -\frac{R_F}{R_L}$$

(iv) Transconductance amplifiers

$$I_o = \frac{V_B}{R_1}$$

(v) Integrator

$$V_o = -\frac{1}{R_c} \int V_{in}(t) dt$$

(vi) Differentiator

$$V_o = \frac{R_c C_{in}}{t} \cdot \frac{dV_{in}}{dt}$$

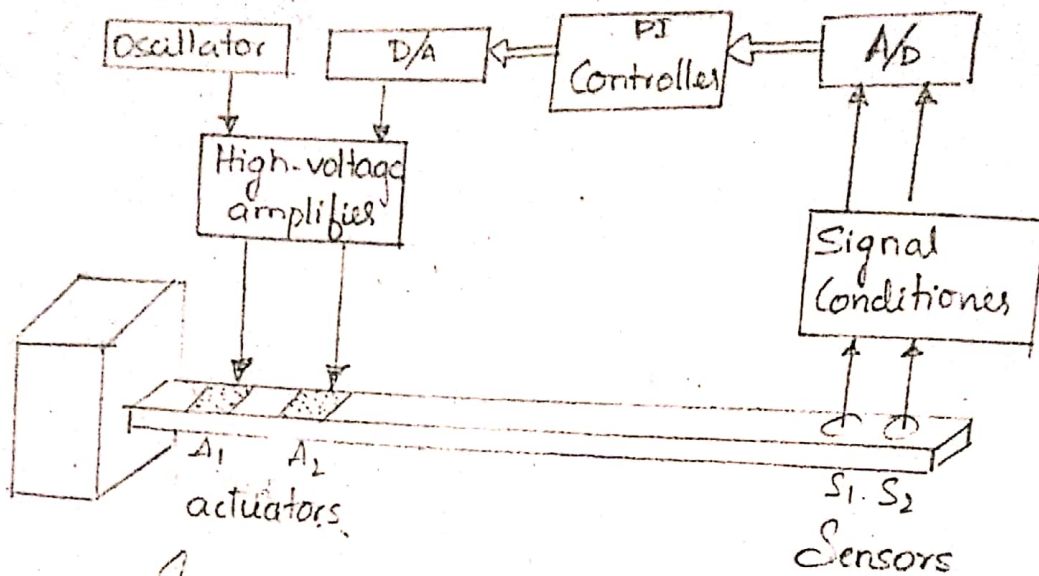
4M



## PART - 2

Q<sub>3</sub>

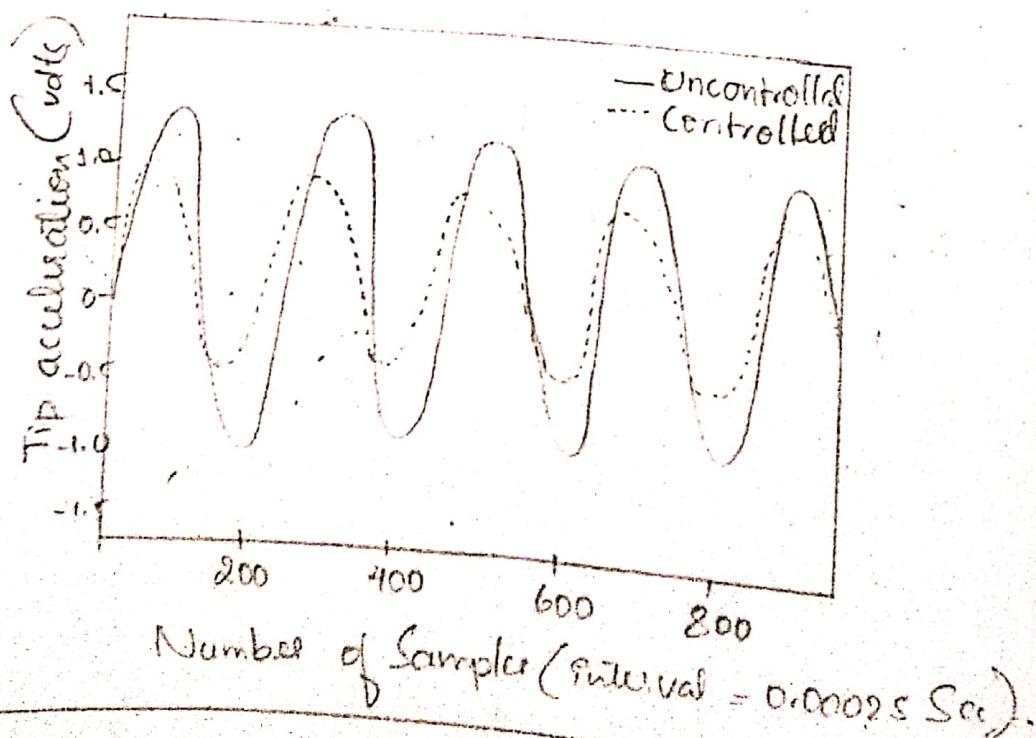
### Vibration Control of beams in microsystems



Schematic diagram of Control System.

Explanation of vibration control of beams in microsystems.

Experimental results showing the response of the sensor with and without the PI controller.



Q4. Bulk micro-machining

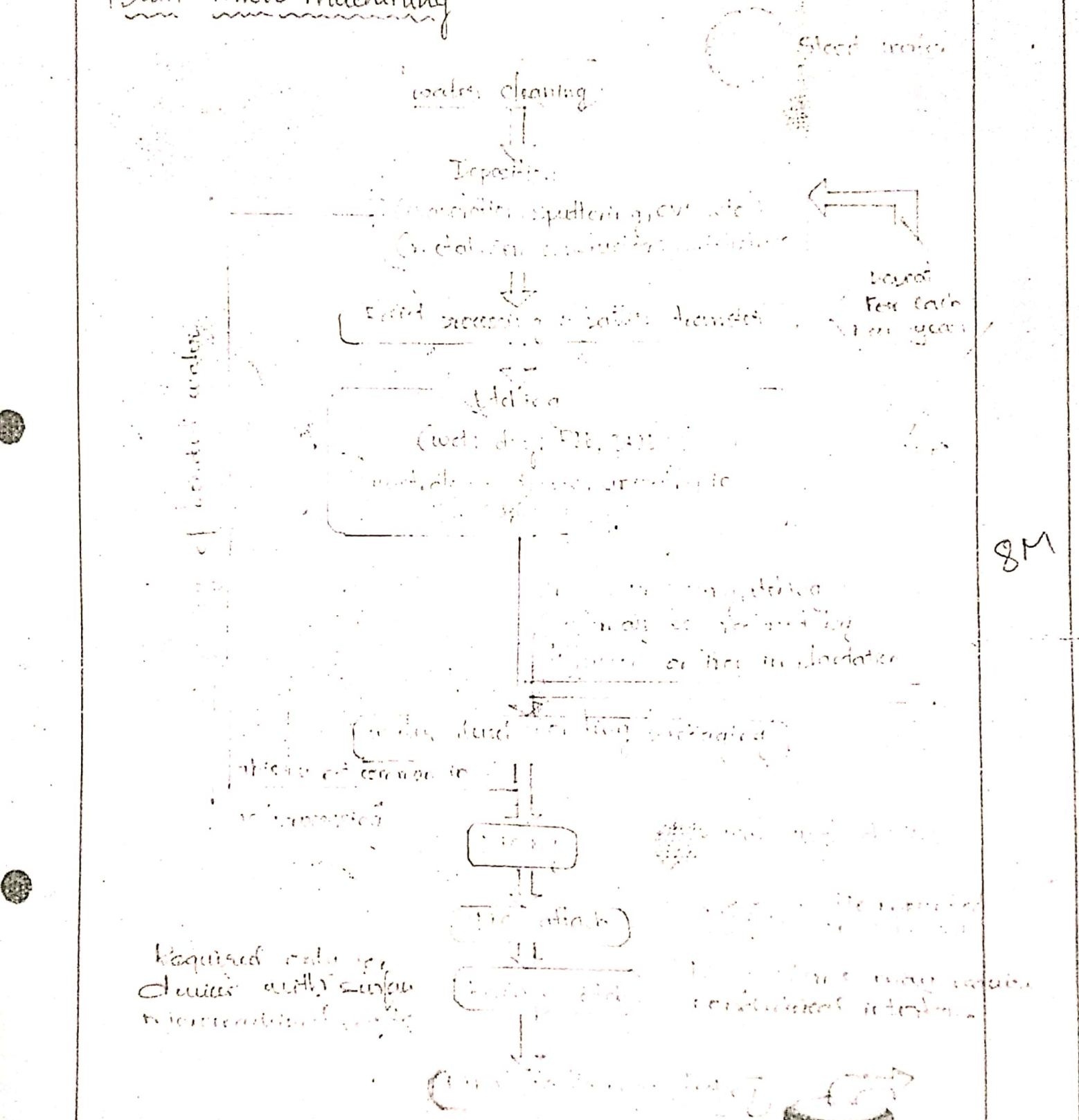


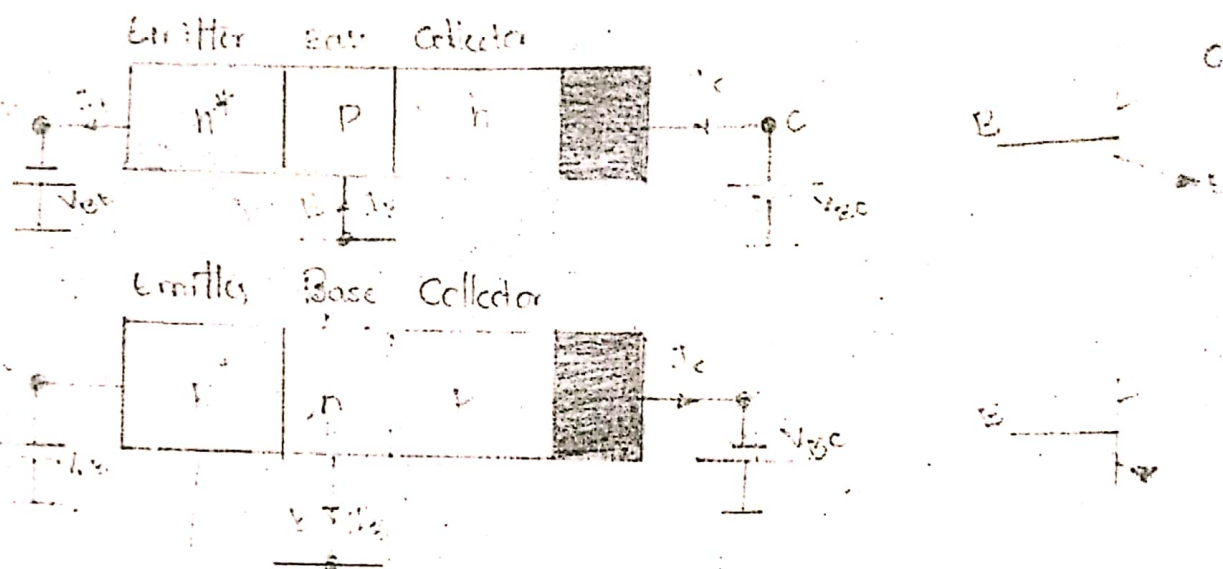
Fig: Flow chart of process steps in the fabrication of microsystems.  
Explanation of Bulk micromachining with operation.



Q5

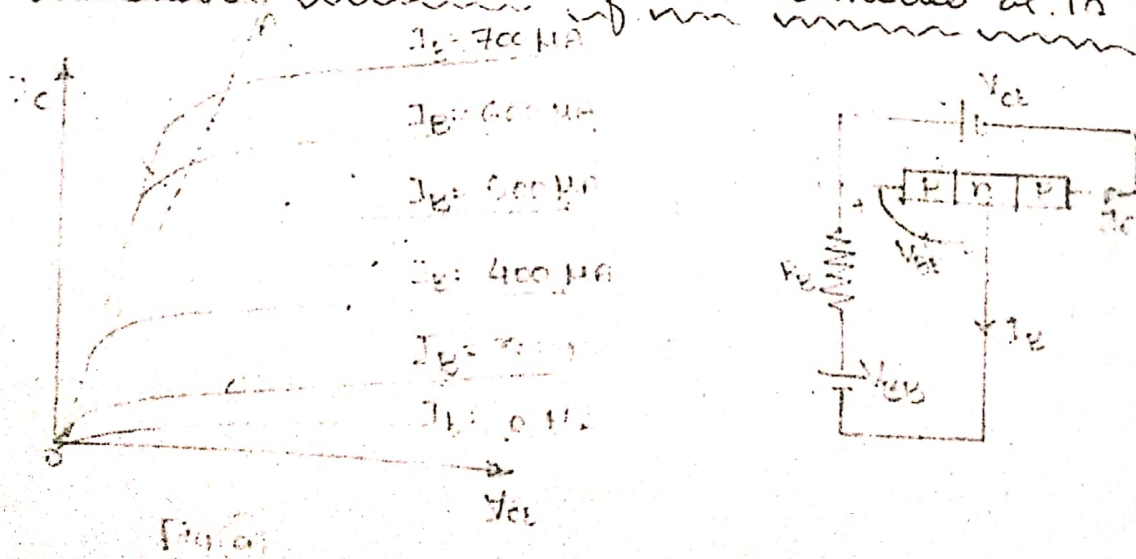
## VI Characteristic of BJT along with Construction.

The bipolar junction transistor is a three-terminal Semiconductor device which finds wide applications for amplifying or switching applications in microelectronics.



Basic structure of (a) an npn & (b) a pnp bipolar Junction transistor. parts (c) and (d) are the circuit Symbols for parts (a) and (b) respectively.

The Output characteristic of BJT connected as in fig-2

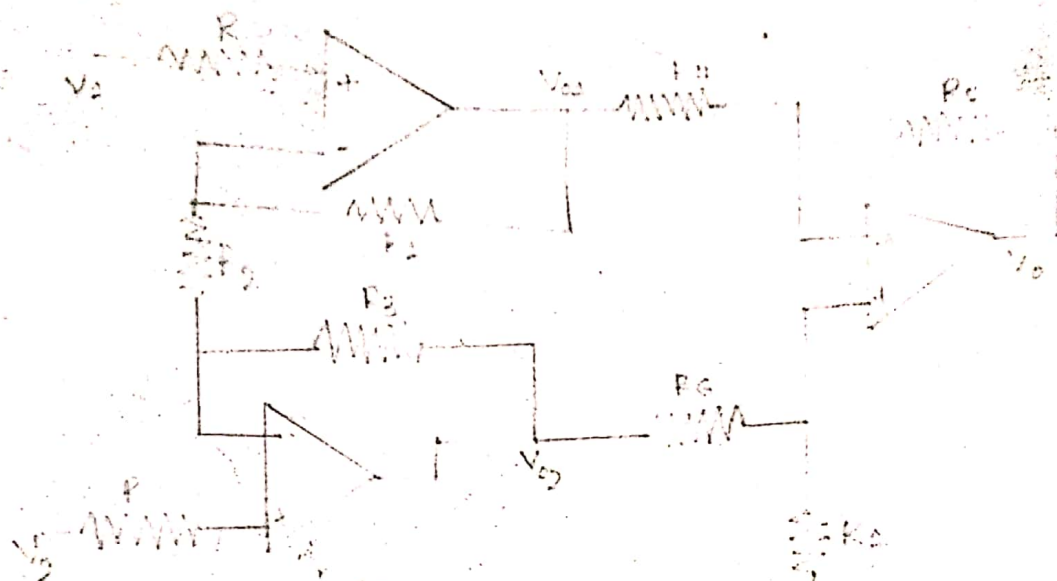


Explanation of construction of BJT.

Fig (b)

Q.6.

Instrumentation Amplifier as a differential voltage amplifier



8M

Explanation of working of Instrumentation Amplifier as a differential voltage amplifier.

$$\frac{V_0}{V_2 - V_1} = \left(1 + \frac{2R_1}{R_2}\right) \frac{R_5}{R_4}$$

PART - 4

ANALOG TO DIGITAL CONVERTER:

The output signals of most physical systems (such as temperature & pressure gauges, flow transducers) are analog or continuous functions of time. However these functions signals must be converted into binary form to enable processing in the digital domain & take advantage of their efficiency & reliability. The circuit performs this conversion is called an analog to digital converter.

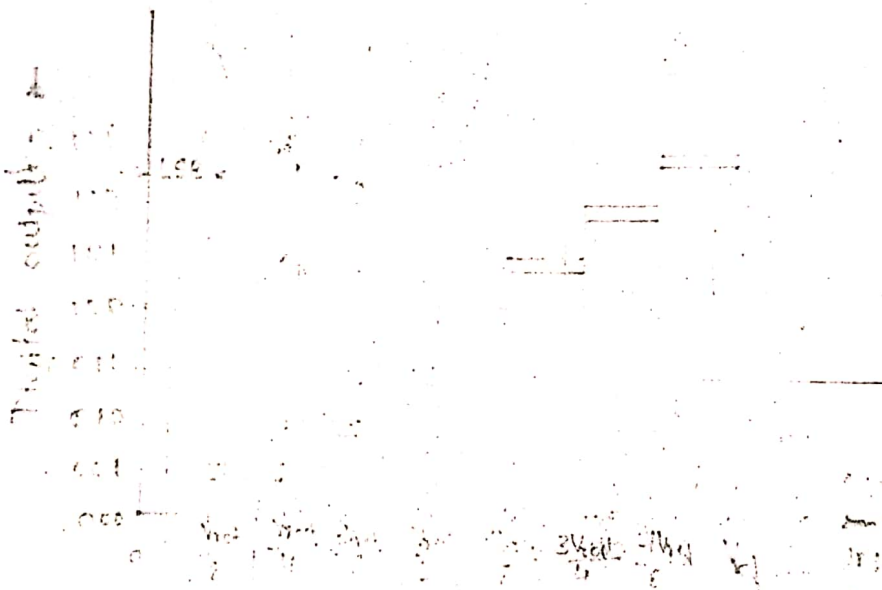


Analog input

ADC

000	(0V - 1V)
001	(1V - 2V)
010	(2V - 3V)
011	(3V - 4V)
100	(4V - 5V)
101	(5V - 6V)
110	(6V - 7V)
111	(7V - 8V)

Three-bit ADC input/output scheme.

(a) Digital outputPHASE LOCKED LOOP

The phase-locked loop (PLL) is one of the basic building blocks of electronic circuits used in several applications such as motor-speed controllers, filters, frequency-synthesized transmitters, receivers & microsystems. As illustrated in Fig (a) the PLL consists of a phase detector, a low pass filter (LPF), dc amplifier & a voltage-controlled oscillator (VCO).

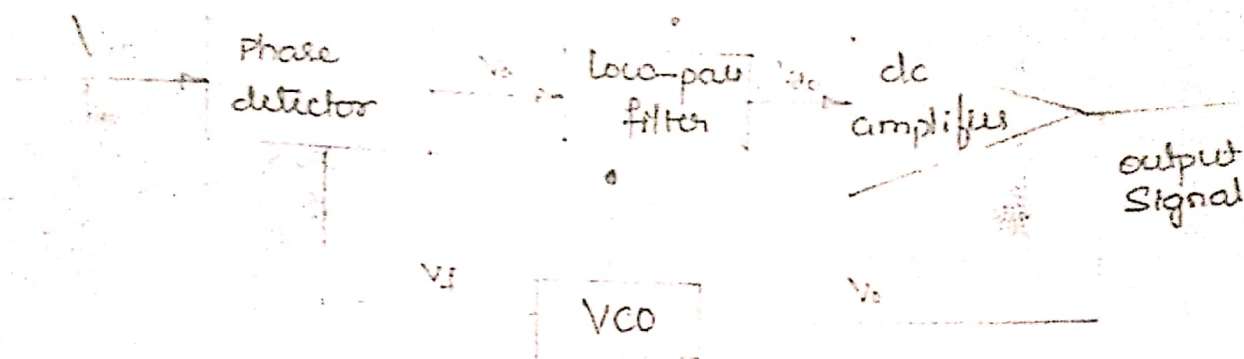
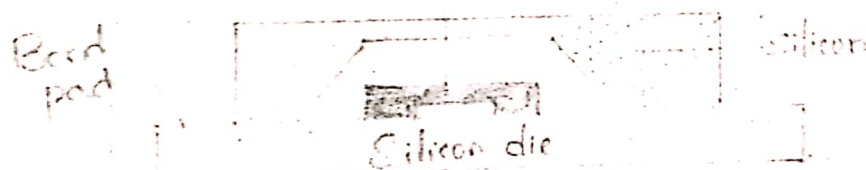


fig: Block diagram showing the operating principle of a PLL.

PART - 5

## 29. Reliability & key failure mechanisms in microsystems

Reliability: Studies and mechanism of failure  
Die with microstructures



The understanding of reliability of systems comes from the knowledge of its failure behaviour & the failure mechanisms. The common failure mechanisms of microsystems are as follows.

(Explanation of following terms).

1. Striction (Explanation)
2. Wear (Explanation)
3. Delamination (Explanation)
4. Damping (Explanation)
5. Fatigue (Explanation)
6. Mechanical Failure (Explanation).

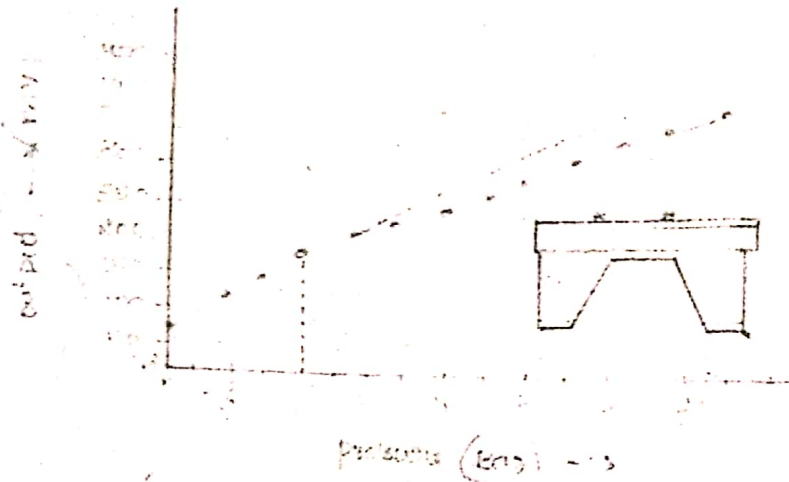
2M



Q.10.

Characteristics & performance parameters of pressure sensor

Typical characteristic of pressure sensor



Explanation of the following

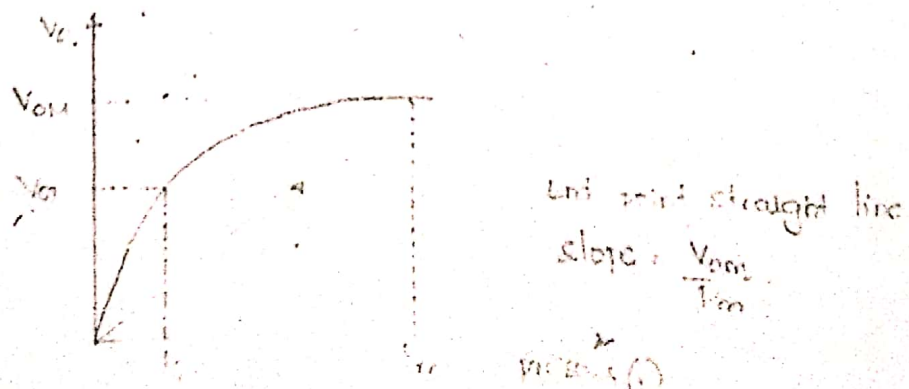
(1) Sensitivity ( $S$ )

$$S = \frac{\Delta V_o}{\Delta P} \frac{1}{V_{IN}} = \frac{\Delta R}{\Delta P} \frac{1}{R}$$

(2) Offset voltage ( $V_{OFF}$ )

$$NL_f = \frac{V_{01} - (V_{OM}/P_m) P_i}{V_{OM}} \times 100\%$$

(3) Non linearity in piezoresistive pressure sensor.



# MICRO AND SMART SYSTEMS TECHNOLOGY (15MT54) QUESTION BANK

## MODULE 1

1. What are smart systems? Explain the components of a smart system with the help of a block diagram.
2. Mention the applications of smart materials and microsystems.
3. What is miniaturization? Mention the need and advantages of miniaturization of systems.
4. With the help of a neat block diagram explain the multidisciplinary nature of micro system.
5. What are micro systems? Explain the components of micro system along with the applications.

## MODULE 2

1. Explain sensors, actuators, and systems with their salient features.
2. What are sensors, and explain the working principle of silicon capacitive accelerometer with diagram.
3. Explain working principle of piezoresistive pressure sensor.
4. With a short note on portable blood analyzer.
5. Explain micro system as micro sensor and micro actuator with block diagram.
6. Explain various blocks in typical smart system and compare each components of system with that of a biological system.
7. What are smart materials, mention different types of smart materials, explain working principle of any two smart materials.
8. Explain micro sensors and micro actuators.
9. Explain the working principle of piezo-electric based inkjet print head, magnetic micro relay, magnetic micro relay, electrostatic comb drive.
10. With the neat sketch explain the silicon micro mirror array used for video projection.

## MODULE 3

1. With neat sketch explain silicon wafer preparation.
2. What do you mean by thin film deposition? Mention the different types of thin film deposition? Explain any one.
3. What is lithography? Explain with neat sketch photo lithography/



4. Explain the sputtering and chemical vapor deposition technique, with neat diagram and equations.
5. Explain the different types of etching with relevant diagrams, chemical equations and etchants.
6. Explain surface micromachining to realize a cantilever structure with neat pictorial representations.
7. Define etch stop? Briefly explain the different methods used to stop etching.
8. With the help of neat sketch explain various steps involved in lift off technique.
9. Write a short note on the following (i) Dry etching (ii) Wet etching (iii) Isotropic etching (iv) Anisotropic etching
10. Differentiate between positive photoresist and negative photoresist.

#### **MODULE 4**

1. With the neat sketch explain enhanced MOSFET with VI characteristics.
2. Briefly explain the different Op-Amp Based circuits.
3. With the neat circuit diagram explain integration of MOSFET with pressure sensor.
4. Explain the vibration control of beams in microsystems with neat sketch
5. Explain the VI characteristics of BJT along with constructions.
6. Define the bulk micromachining. With the flow chart explain it/

#### **MODULE 5**

1. Explain the bulk microchined accelerometer.
2. Explain the instrumentation amplifiers as differential voltage amplifier.
3. Explain phase locked loop with a neat block diagram
4. Reliability and key failure mechanisms and performance parameters of pressure sensor.
5. Explain basic Op Amp circuits and their applications.
6. Explain analog to digital converter.

## MICRO AND SMART SYSTEMS TECHNOLOGY

### Assignment-1

1. What are smart systems? Explain the components of a smart system with the help of a block diagram.
2. Mention the applications of smart materials and micro systems.
3. What is miniaturization? Mention the need and advantages of miniaturization of systems.
4. With the help of a neat block diagram explain the multidisciplinary nature of micro system.
5. What are micro systems? Explain the components of micro system along with the applications.
6. Explain sensors, actuators, and systems with their salient features.
7. What are sensors and explain the working principle of silicon capacitive accelerometer with diagram.
8. Explain working principle of piezo-resistive pressure sensor.
9. With a neat sketch explain conductometric gas sensor.
10. Write a short note on portable blood analyzer.
11. Explain micro system as micro sensor and micro actuator with block diagram.
12. Explain various blocks in typical smart system and compare each components of system with that of a biological system.
13. Make a comparison between micro electronics and micro system technologies.
14. Mention the technical reasons for process of miniaturization.
15. What are smart materials, Mention different types of smart materials, explain working principle of any two smart materials.
16. Explain micro sensors and micro actuators.





10EC752

Seventh Semester B.E. Degree Examination, Dec.2014/Jan.2015  
**Micro & Smart System Technology**

Time: 3 hrs.

Max. Marks: 100

Note: Answer FIVE full questions, selecting  
at least TWO questions from each part.

**PART - A**

- 1 a. What is microsystem? Make a comparison between micro electronics and micro systems. (08 Marks)  
b. Explain the typical smart system with a block diagram. (08 Marks)  
c. Mention the technical reasons for miniaturization. (04 Marks)
- 2 a. Explain with a neat diagram the process steps involved in the construction of silicon capacitive accelerometer and state principle of operation. (12 Marks)  
b. Explain the principle of operation of DMD chip. (08 Marks)
- 3 a. With the help of neat sketches explain the process steps involved in realizing a cantilever structure by surface micro machining. (12 Marks)  
b. Define etch stop? Briefly explain the different methods used to stop etching. (08 Marks)
- 4 a. For a straight beam in pure bending, show that the bending stress  $\sigma_x$ , the bending moment  $M$  and area moment of inertia  $I$  are related by,  $\sigma_x = \frac{M}{I} y$ . (10 Marks)  
b. Explain various scaling issues to be considered in miniaturization. (10 Marks)

**PART - B**

- 5 a. Explain the need for using numerical methods in micro system design. (10 Marks)  
b. Derive the shape function for a rod of finite element having length  $L$  and axial rigidity  $EA$ . (10 Marks)
- 6 a. Explain with a neat schematic how to measure capacitance or charge from switched capacitor circuits. (10 Marks)  
b. Describe a role of implementing a PID controller for a smart system design. (10 Marks)
- 7 a. Briefly explain the different types of microsystem packages. (10 Marks)  
b. Explain the reliability and key mechanism that are essential in micro system. (10 Marks)
- 8 Write short notes on the following:  
a. Active vibration control.  
b. Finite element method.  
c. Thin film deposition.  
d. Soft lithography. (20 Marks)

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**Seventh Semester B.E. Degree Examination, Dec.2015/Jan.2016**  
**Micro and Smart Systems Technology**

Time: 3 hrs.

Max. Marks: 100

*Note: Answer any FIVE full questions, selecting atleast TWO questions from each part.*

**PART - A**

- 1
  - a. Discuss the applications of Micro system in the Aerospace Industry. (06 Marks)
  - b. With the help of a neat block diagram, explain the multidisciplinary nature of micro system design and manufacturing. (10 Marks)
  - c. Discuss evolution of micro fabrication. (04 Marks)
- 2
  - a. Explain the principle of operation of Silicon Capacitive Accelerometer, with a neat diagram. (06 Marks)
  - b. Discuss in digital Piezoresistive pressure sensor, with a schematic diagram. (06 Marks)
  - c. Write short note on Magnetic Micro relay. (04 Marks)
  - d. Explain the principle of operation of Portable Blood Analyzer. (04 Marks)
- 3
  - a. Explain Czochralski method for growing Single – Crystal Silicon. (06 Marks)
  - b. Discuss the process of preparation of Silicon Dioxide, Silicon Nitride and Polysilicon using Chemical Vapor Deposition. (08 Marks)
  - c. With the help of a neat diagram, explain the different process steps involved in the fabrication of micro system. (06 Marks)
- 4
  - a. With the help of appropriate equations, discuss scaling dynamic forces. (04 Marks)
  - b. Discuss the effect of Residual Stress Gradient on a Cantilever beam. (06 Marks)
  - c. Using FEM (Finite Element Method) analyze a stepped bar. (10 Marks)

**PART - B**

- 5
  - a. Discuss the analysis of Piezoelectric Bimorph Cantilever Beam using Finite Element Method. (10 Marks)
  - b. Discuss the dynamics of the Simplest Lumped Electro Mechanical Method. (10 Marks)
- 6
  - a. Explain Instrumentation Amplifier as a Differential Voltage Amplifier. (06 Marks)
  - b. Explain Phase – Locked Loop, with a neat block diagram. (06 Marks)
  - c. With appropriate mathematical equations, explain State – Space Modeling. (08 Marks)
- 7
  - a. Discuss the special issues in Micro system packaging. (06 Marks)
  - b. Briefly explain various types of micro system packages. (06 Marks)
  - c. With the help of a neat diagram, explain Die – Level Packaging in detail. (08 Marks)
- 8
  - a. With appropriate equations, discuss the various design considerations of Piezoresistive Pressure sensor. (10 Marks)
  - b. Explain active vibration control in beams using Lead Zirconate Titanate Transducers. (10 Marks)



**Seventh Semester B.E. Degree Examination, June/July 2017**  
**Micro and Smart System Technology**

Time: 3 hrs.

Max. Marks: 100

Note: Answer FIVE full questions, selecting at least TWO questions from each part.

**PART - A**

1. a. Explain the various blocks in typical smart system and compare each component of with that of a biological system. (10 Marks)  
b. Make a comparison between micro electronics and Microsystems technologies. (05 Marks)  
c. Mention the need and advantages of miniaturization of machine and devices. (05 Marks)
2. a. With necessary sketches, explain the working principle of silicon capacitive accelerometer and mention its advantages and applications. (08 Marks)  
b. Briefly explain the following : (12 Marks)  
i) Magnetic micro-relay ii) Piezo-electric inkjet actuator.
3. a. With necessary sketches, explain the key processes involved in photolithography. (10 Marks)  
b. With the help of neat sketches, explain various steps involved in lift-off technique. (10 Marks)
4. a. With the help of neat sketches, explain the various steps involved in the fabrication of a cantilever structure by surface micromachining. (10 Marks)  
b. Explain the Anode bonding process for microfabrication.. (05 Marks)  
c. Explain various scaling issues to be considered in miniaturization. (05 Marks)

**PART - B**

5. a. What is Finite element method? Briefly explain its procedure using flow-chart. (10 Marks)  
b. Obtain an expression for the stresses developed in a two-bar assembly of stepped bar with fixed ends. (10 Marks)
6. a. With a neat schematic of instrumentation amplifier, mention its characteristics and obtain expression for its differential gain. (10 Marks)  
b. With necessary schematics and waveforms, explain the operation of switched capacitor circuit for capacitance measurement. (10 Marks)
7. a. Design an inverting amplifier with closed loop voltage gain -100 and feedback resistance of  $100\text{k}\Omega$ . Also find its output voltage for a input voltage of  $0.5\mu\text{V}$ . (06 Marks)  
b. Briefly explain the various possibilities of monolithic integration of CMOS and microsystem. (09 Marks)  
c. Mention the general considerations in packaging design. (05 Marks)
8. Write a short note on the following :  
a. Isotropic etching  
b. Dry etching  
c. Wire bonding  
d. LIGA process. (20 Marks)



USN

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10EC752

**Seventh Semester B.E. Degree Examination, Dec.2016/Jan.2017**  
**Micro & Smart Systems Technology**

Time: 3 hrs.

Max. Marks 100

*Note: Answer FIVE full questions, selecting  
at least TWO questions from each part.*

**PART - A**

1. a. Explain the components of a smart system with the help of a block diagram. List the general requirements of a smart system. (10 Marks)  
b. Mention the applications of smart materials and micro system. (10 Marks)
2. a. Describe the working of silicon capacitive accelerometer. (07 Marks)  
b. Explain the principle of operation of piezoelectric based inkjet printhead. (07 Marks)  
c. Explain the operation of a magnetic microrelay (06 Marks)
3. a. With a neat diagram, describe the process of silicon wafer preparation. (08 Marks)  
b. Describe surface micromachining technique with the help of a suitable example. (08 Marks)  
c. Differentiate between positive photoresist and negative photoresist. (04 Marks)
4. a. Describe in detail scaling of electromagnetic forces and electrostatic forces. (10 Marks)  
b. Describe the concept of coupled electromechanics in detail. (10 Marks)

**PART - B**

5. a. Describe in detail the weighted residual technique (10 Marks)  
b. Explain finite element method in detail. (10 Marks)
6. a. Describe the working of a MOSFET with a suitable diagram. (10 Marks)  
b. Explain how to check the stability of a system using Routh Hurwitz criterion. (10 Marks)
7. a. List and explain the issues in microsystem packaging. (10 Marks)  
b. Describe any four packaging technologies used in microsystem. (10 Marks)
8. a. With a neat diagram, explain the working of a piezoresistive pressure sensor and define the terms sensitivity and offset voltage. (10 Marks)  
b. Describe how to perform active vibration control of a beam. (10 Marks)

\* \* \* \* \*



**THE OXFORD COLLEGE OF ENGINEERING**  
**DEPARTMENT OF MECHATRONICS ENGINEERING**

**V- SEM RESULT ANALYSIS AFTER REVALUATION - 2019(ODD SEMESTER)**

Sub Code	Subject	Faculty Name	Total No. of students	No. of students appeared	FCD	FC	SC	Pass %	Fail	Pass	Absent	VH
15MT51	DESIGN OF MACHINE ELEMENT	Mr. CHETHAN	62	62	0	6	35	66	21	41	0	0
15MT55	WIRELESS NETWORK AND COMMUNICATION	Ms. Rani Aishwarya SN	62	62	12	18	29	95	3	59	0	0
15MT52	VIRTUAL INSTRUMENTATION	Dr. RAJESWARI	62	61	45	10	6	98	1	60	1	0
15MT56	AUTOMATION IN MANUFACTURING	Mr. THIRUMURUGAN	62	61	24	22	15	100	0	61	1	0
15MT53	HYDRAULICS AND PNEUMATICS	Mr. THIRUMURUGAN	62	62	18	23	20	100	0	62	0	0
15MT54	MICRO AND SMART SYSTEM TECHNOLOGY	Mr. DHANANJAYA V	62	62	22	15	13	97	1	60	0	1
15MTL57	VIRTUAL INSTRUMENTATION LAB	Dr. RAJESWARI	62	62	58	4	0	100	0	62	0	0
15MTL58	MICRO AND SMART SYSTEM TECHNOLOGY LAB	Mr. DHANANJAYA V	62	62	62	0	0	100	0	62	0	0

N.   
**Principal**

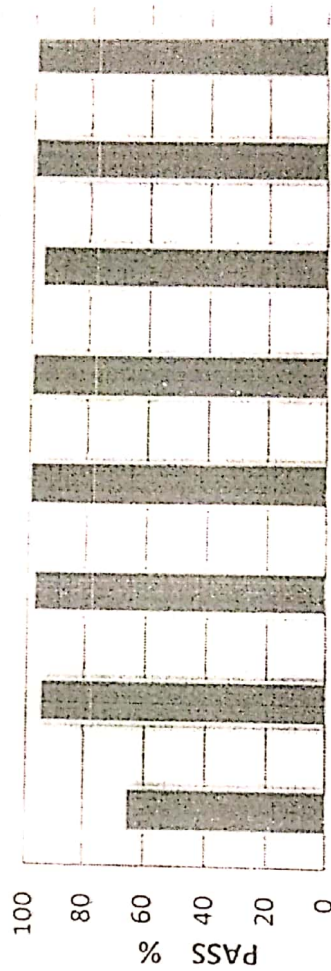
**Department of Mechatronics Engineering**  
**The Oxford College of Engineering**  
 Bommanahalli, Hosur Road - 560 068.

**Dr. R.V. PRAVEENA GOWDA**  
**PRINCIPAL**  
 The Oxford College of Engineering  
 Bommanahalli, Hosur Road  
 Bengaluru-560 068.

Subject Wise Topper Details		
Subject Cod	Name of the Student	Marks
15MT51	SANDEEP S	69
15MT551	HANUSHITHA K	85
15MT52	HANUSHITHA K	96
15MT562	AMOOLYA G	86
15MT53	PREETHAM KUMAR B	86
15MT54	AFNAN PASHA	85
15MTL57	AFNAN PASHA	98
15MTL58	KANNIKA V PAI	98

TOPPERS	NAMES	Marks ( %)
I	HANUSHITHA K	84
II	AMOOLYA G	82
III	AFNAN PASHA	82
IV	MEGHANA V	79
V	PREETHAM KUMAR B	79
No of Subj.Failed		No of Subjects
1 subject		19
2 subjects		1
3 Subjects		0
More than 3 subjects		4

Overall Performance	65.00%	
No. of students Results declared :	62	
Results Withheld :	0	
PASS	40	65%
FCD	21	34%
FC	18	29%
SC	1	2%
FAIL	22	35%



Subject Code

15MT51 15MT551 15MT52 15MT562 15MT53 15MT54 15MTL57 15MTL58

N. Jayar

Dr. R.V. PRAVEENA GOWDA  
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Bengaluru-560 068.





**THE OXFORD COLLEGE OF ENGINEERING**  
HOSUR ROAD, BOMMANAHALLI, BANGALORE - 68  
Department of Mechatronics Engineering

**SUBJECT CODE / SUBJECT NAME: 15MT54 MICRO AND SMART SYSTEM TECHNOLOGY**

**NOTE: COURSE OUTCOME CODE NEEDS TO BE IN THIS FORMAT - C232.1**

(ie first digit is year, second digit is semester, third digit is subject code after dot it is first outcome means it should be written 1 second means 2 third means 3 etc -- For eg if it is network analysis it should be C232.1)

Please all of you select 6 outcomes for your subject

Kindly see to that CO should relate to your subject

First and second CO should be dependent on the modules which will be kept for Internal 1

Third and fourth CO should be dependent on the modules which will be kept for Internal 2

Fifth and sixth CO should be dependent on the modules which will be kept for Internal 3

COURSE OUTCOME CODE	DESCRIPTION
C354.1	Know the basic concept of micro and smart system technology.
C354.2	Understand the need of micro size machines and devices.
C354.3	Know how this micro system technology is evolved in all fields of science and technology
C354.4	Know the smart materials and their characteristics for the smart system applications.
C354.5	Understand the working of different sensors for smart system applications.
C354.6	Know how the different components of smart systems are integrated with each other.

**MARK - 3, 2 AND 1 (depending on which CO is matching with which attribute and how it is mapped)**

(Please give the explanation for the mapping at the back side of the paper)

Graduate Attributes of NBA	CO - 1	CO - 2	CO - 3	CO - 4	CO - 5	CO - 6
PO1: Apply the knowledge of mathematics, science, engineering fundamentals, and an engineering specialization to the solution of complex engineering problems.	3	1	1	1		
PO2: Identify, formulate, review research literature, and analyze complex engineering problems reaching substantiated conclusions using first principles of mathematics, natural sciences, and engineering sciences.	2	2	2	2	3	1
PO3: Design solutions for complex engineering problems and design system components or processes that meet the specified needs with appropriate consideration for the public health and safety, and the cultural, societal, and environmental considerations.	2	2	2	2	2	2
PO4: Use research-based knowledge and research methods including design of experiments, analysis and interpretation of data, and synthesis of the information to provide valid conclusions		3	3	2	2	
PO5: Create, select, and apply appropriate techniques, resources, and modern engineering and IT tools including prediction and modelling to complex engineering activities with an understanding of the limitations	2					
PO6: Apply reasoning informed by the contextual knowledge to assess societal, health, safety, legal and cultural issues and the consequent responsibilities relevant to professional engineering practice.	2	1	3	2	2	
PO7: Understand the impact of the professional engineering solutions in societal and environmental contexts, and demonstrate the knowledge of, and need for sustainable development.						
PO8: Apply ethical principles and commit to professional ethics and responsibilities and norms of the engineering practice.						
PO8: Function effectively as an individual, and as a member or leader in diverse teams, and in multidisciplinary settings.						
PO10: Communicate effectively on complex engineering activities with the engineering community and with society at large, such as, being able to comprehend and write effective reports and design documentation, make effective presentations, and give and receive clear instructions.	2	1	2	2	1	
PO11: Demonstrate knowledge and understanding of the engineering and management principles and apply these to one's own work, as a member and leader in team, to manage projects and in multidisciplinary environments	2	1	3	3	1	
PO12: Recognize the need for, and have the preparation and ability to engage in dependent and life-long learning in the broadest context of technological change.	3	2	2	2	2	2

*Ashoka DV*  
FACULTY NAME

*H. Raju*  
PRF

*[Signature]*  
HOD / MT



## Co-PSO justification:

- C476.1 pol. Apply the knowledge of mathematics Science, Engineering fundamentals and on Engineering Specialization to the solution of Complex engineering problems.
- C476.1. pol: use research based knowledge on research methods including design of experiments.
- C352.3 pol: - Apply the knowledge in two dimensional Transformation & homography co-ordination.
- C302.1 pol, the Basic knowledge of the drawing and clipping representation used to apply in engineering computer graphics problems.
- C352.2 pol, using two dimensional transformation. find the engineering problem solution.
- C352.3 pol - Apply using two dimensional transformation find the engineering problem solution.





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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU, Belgaum)

## STUDENT MENTOR REGISTER

Name of the Student	:	<u>B R M Thisignayeshwari</u>
USN	:	<u>10X18EE009</u>
Batch	:	<u>2018-19</u>
Branch	:	<u>EEE</u>

PRINCIPAL

The Oxford College of Engineering  
Bommanahalli, Hosur Road







## **Vision**

*To be a respected and most sought after Engineering Educational Institution engaged in equipping individuals capable of building learning Organizations in the new Millennium*

## **Mission**

*To Develop Competent students with good value systems and face challenges of the continuously changing world.*







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## STUDENT MENTOR REGISTER



Name of the Student : B.R.M. THIRIGUNYESHWARI

USN : 10X18EED09

Batch : 2018 - 22

Branch : ELECTRICAL & ELECTRONIC  
ENGINEERING





# THE OXFORD COLLEGE OF ENGINEERING

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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU, Belagavi)

Sl.No.	Name of the Mentor	Designation	Mentor Period		Signature of the Mentor
			From	To	
1.	Sumithra T.L	Asst. Prof	27/8/18	Dec 2018	Th S m
2.	Sumithra T.L	AP	Jan -19	June-19	Th S m
3.	Sumithra T.L	Asst-Prof	July 2019	Dec 2019	Th S m
4.	Sumithra T.L	Asst-Prof	Jan 2020	July 2020	Th S m
5.	Sumithra T.L	Asst. Prof	Aug 2020	Jan 2021	Th S m
6.	Sumithra T.L	Asst. Prof.	Feb 2021	July 2021	Th S m
7.					
8.					



**TO BE FILLED WITH BLOCK LETTERS ONLY**

Name of the Student : B.R.M. THIRIGUNYESHWARI

University Seat Number : 10X18EE009

Degree/Branch : ELECTRICAL AND ELECTRONIC ENGINEERING

Date of Birth (DD/MM/YYYY) : 05/05/1999

Religion/ Community/Caste : HINDU LINEATATS JANMAGA

Year of Admission : 2018 Nature of Admission: CET/MGMT. CETNo. AZQ61 CET Rank 111654

Hosteller /Day Scholar : DAY SCHOLAR

Languages Known : ENGLISH, KANNADA, HINDHI

Blood Group : A+ Height & Weight : 5.0 4 70

Mobile No./E-Mail. Id : 9148224666 / B.R.M. THIRIGUNYESHWARI@YAHOO.COM

Name	Qualification /Occupation Designation	Office Address With Phone No.	Mobile No./Email Id.
Name of Father B.R.M. HEMA MAHESHWAR.	B.E. (CS) SOFTWARE ENGINEER.	KALYANI PLAZANA, EPIP ZONE, -2, WHITEFIELD, BANGALORE, KARNATAKA - 560066	9945500094 = HEMA-MAHESHWAR@YAHOO.CO.IN
Name of Mother M. G. SHOBHA MANGALA	B.COM HOUSE WIFE	9148223666	9148223666
Name of Guardian			



## Address of Communication:

a) Permanent Address

H/No. 555, 3<sup>rd</sup> Cross, RBT Layout,  
Near Brigade Millenium, Bangalore,  
Karnataka

Pin: .....

Phone No: 9945500094

b) Communication Address

H/No. 555, 3<sup>rd</sup> Cross, RBT Layout,  
Near Brigade MILLENIUM, Bangalore,  
Karnataka

Pin: .....

Phone No: 9945500094

Method of Examination Preparation


: Daily studying

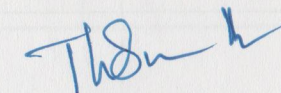
Fluency in English? Yes/No

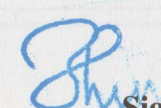
: YES

How do you prepare to improve yourself in spoken english :

Reading books,

  
Signature of the Student

  
Signature of the Mentor

  
Signature of the HOD





# THE OXFORD COLLEGE OF ENGINEERING

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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU, Belagavi)

## Parents - Teacher Meeting

Sl.No.	Date of Visit	Reason for Visit	Remarks from Class Teacher/ HOD	Signature of Mentor	Signature of Parent
1	4/12/18	To know the academic status	Attendance to be improved.	ThS	
2					
3	21/5/19	To inform the attendance status	Poor attendance	ThS	
4	30/11/19	To collect hall ticket	Condonation list	ThS	
5					
6					
7					
8					

Signature of the Mentor

Signature of the HOD



### SCHOLARSHIP DETAILS

Sl.No.	Academic Year	Class obtained with %	Amount

### SPONSORSHIP

Sl.No	Date of Conference	Conference/ Project Details	Amount

### INTERNSHIP TRAINING

Sl. No.	Period	Name of the Organization



# I SEMESTER

## Attendance & Performance in Internal Assessment Test

Max Marks: 40

Sl. No	Sub Code	Subject Name	IA Test-I				IA Test-II				IA Test-III				Final Marks
			Attendance			Marks	Attendance			Mark s	Attendance			Marks	
			CT	CA	%		CT	CA	%		CT	CA	%		
						30				30				30	40
1	18MAT11	Calculus & Linear Algebra	21	10	48	17	37	22	59	11	65	43	66	15	24
2	18CHE12	Engg. chemistry	22	11	50	19	44	25	57	29	67	44	66	29	33
3	18CPS13	C programming	18	17	94	20	30	21	70	18	55	42	76	23	30
4	18ELN14	Basic Electronics	20	12	60	12	31	18	58	11	58	46	79	23	25
5	18ME15	Elements of Mechanical Engg.	20	16	80	14	30	23	77	19	51	39	76	23	26
6	18EGH18	Technical English - I	10	4	40	13	14	8	57	11	24	18	75	21	23
7	18CHE16	Engg. chemistry Lab	4	3	75	—	8	6	75	—	14	14	100	—	30
8	18CPL17	C prog. Lab	6	6	100	—	9	9	100	—	11	11	100	—	37

CT=No. of Classes Taken CA=No. of Classes Attended

Overall % of attendance in I semester: 79.8 %

Signature of the Student

Signature of the Mentor

Signature of the HOD



Counselling	Date/Time	Identified Shortfalls in the Academic Performance	Student Remarks	Signature	
				Student	Mentor
Counselling After 1 <sup>st</sup> IA Test	29/10/18	Poor attendance, Average performance, Needs improvement	will study well.	Hoique	Ln
Counselling After 2 <sup>nd</sup> IA Test	01/12/18	Irregular to classes, No improvement seen in studies & attendance	will attend the classes regularly.	Hoique	Ln
Counselling After 3 <sup>rd</sup> IA Test	12/01/19	Average marks; Very irregular to classes	will improve my marks and attendance	Hoique.	Ln

Hoique.  
Signature of the Student

Ln  
Signature of the Mentor

Shunni  
Signature of the HOD



# I SEMESTER UNIVERSITY RESULTS

Arrears (if any) : NIL

SGPA/%: 6.5 / 58.38 %

CLASS OBTAINED : SC

Sub Code	18MAT11			18CHE12			18CPS13			18ELE14			18MEEL15			18CHEL17			18CPSL17			18EGH18		
SubName	Calculus & Linear Algebra			Engg. Chemistry			C prog.			Basic Electronics			Mechanical Engg.			Chemistry Lab			C prog. Lab			Technical English.		
Month & Year	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T
Jan 2019	24	31	55	33	30	63	30	32	62	25	21	46	26	21	47	30	42	72	37	31	68	23	31	54

IA=Final IA Marks

Ext.= External Exam Marks

T=Total(IA+Ext.)

467

800

## Counselling after University Results

Date of Counselling	Time	Mentor Notes	Student Remarks
20/3/19	2.30 to 2.45 pm	Have to improve the marks and get first class	Sorry, will improve marks for first class in next sem.

Signature of the Student

Signature of the Mentor

Signature of the HOD





# THE OXFORD COLLEGE OF ENGINEERING

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(Approved by AICTE, New Delhi, Accredited by NBA, New Delhi & Affiliated to VTU, Belagavi)

## UNDERTAKING BY STUDENT

I, B.R.M. Jhigunyeswari, USN 10X18EE009, studying B.E in 1<sup>st</sup> semester, am aware that I have attendance shortage as on today and the statutory requirement for appearing VTU exam is 85%.

I assure that I shall be regular to the classes from now onwards. In case, I am detained due to shortage of attendance, I am solely and wholly responsible for detention.

Date: 11/9/19

Ymire  
Signature of the Student

## UNDERTAKING BY PARENT

I am aware that my ward \_\_\_\_\_, USN studying B.E in \_\_\_\_\_ semester is having attendance shortage as of today (Date: \_\_\_\_\_) and the statutory requirement for appearing VTU exam is 85%.

I assure that my ward will be regular to the classes from now onwards. In case, He/She is detained due to shortage of attendance, my ward will solely and wholly responsible for detention.

Date: \_\_\_\_\_

Name of the Parent: \_\_\_\_\_

Relationship: \_\_\_\_\_

Mobile No: \_\_\_\_\_

Ymire  
Signature of the Parent/Guardian



## II SEMESTER

### Attendance & Performance in Internal Assessment Test

Max Marks: 40

Sl. No	Sub Code	Subject Name	IA Test-I				IA Test-II				IA Test-III				Final Marks
			Attendance			Marks	Attendance			Mark s	Attendance			Marks	
			CT	CA	%		CT	CA	%		CT	CA	%		
						30				30				30	40
1	18MAT21	Advanced Calculus	20	11	55	26	42	32	76	23	48	37	77	20	29
2	18PHY22	Engg. Physics	22	13	59	26	48	30	63	27	61	47	77	25	36
3	18ELE23	Basic Electrical Engg.	17	11	65	11	35	21	60	19	48	36	75	17	25
4	18CIV24	Elements of Civil Engg.	20	10	50	0	48	45	94	21	52	51	98	17	23
5	18EGDL25	Engg. Graphics	14	10	71	-	35	20	57	-	46	30	65	-	34
6	18PHYL26	Physics Lab	5	4	80	-	11	10	91	-	13	11	85	-	38
7	18ELEL27	Electrical Lab	5	5	100	-	10	10	91	26	13	11	85	-	30
8	18EGH28	Technical Engg-II	8	5	63	15	17	11	65	17	24	18	75	17	23

CT=No. of Classes Taken      CA=No. of Classes Attended

Overall % of attendance in II semester: 79.63 %

Signature of the Student

Signature of the Mentor

Signature of the HOD



Counselling	Date/Time	Identified Shortfalls in the Academic Performance	Student Remarks	Signature	
				Student	Mentor
Counselling After 1 <sup>st</sup> IA Test	27/4/19	Not attended civil classes.	will attend regularly.	Haique	LM
Counselling After 2 <sup>nd</sup> IA Test	24/5/19	Attendance less; Less score in Basic electrical.	will score more marks.	Haique	LM
Counselling After 3 <sup>rd</sup> IA Test	15/6/19	Less marks in Civil Engg & Electrical Engg.	will work hard.	Haique	LM

Signature of the Student

Signature of the Mentor

Signature of the HOD



## II SEMESTER UNIVERSITY RESULTS

Arrears (if any) : NIL

SGPA/%: 63.63%

CLASS OBTAINED : FC

Sub Code	18MAT21			18PHY22			18ELE23			18CIV24			18EGDL25			18PHYL26			18EEL27			18EGH28		
SubName	Advanced Calculus			Engg. Physics			Basic Electrical Engg.			Engg. Civil			Engg. Graphics			Physics Lab			Electrical Lab			Technical English		
Month & Year	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T
July 2019	29	33	62	36	21	57	25	23	48	23	23	46	34	42	76	38	54	92	30	37	67	23	38	61

IA=Final IA Marks

Ext.= External Exam Marks

T=Total(IA+Ext.)

509  
800

### Counselling after University Results

Date of Counselling	Time	Mentor Notes	Student Remarks
20/8/19	1:45 to 2:55 pm	Can improve in Basic Electrical, Graphics	More → will improve no marks.

Signature of the Student

Signature of the Mentor

Signature of the HOD





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## UNDERTAKING BY STUDENT

I, B.R.M. Jhignyeshwari, USN 10X18EE009, studying B.E in II<sup>nd</sup> semester, am aware that I have attendance shortage as on today and the statutory requirement for appearing VTU exam is 85%.

I assure that I shall be regular to the classes from now onwards. In case, I am detained due to shortage of attendance, I am solely and wholly responsible for detention.

Date: 11/04/19

Jhignyeshwari  
Signature of the Student

## UNDERTAKING BY PARENT

I am aware that my ward \_\_\_\_\_, USN studying B.E in \_\_\_\_\_ semester is having attendance shortage as of today (Date: \_\_\_\_\_) and the statutory requirement for appearing VTU exam is 85%.

I assure that my ward will be regular to the classes from now onwards. In case, He/She is detained due to shortage of attendance, my ward will be solely and wholly responsible for detention.

Date: \_\_\_\_\_

Name of the Parent: \_\_\_\_\_

Relationship: \_\_\_\_\_

Mobile No: \_\_\_\_\_

\_\_\_\_\_  
Signature of the Parent/Guardian



### III SEMESTER

#### Attendance & Performance in Internal Assessment Test

Max Marks: 40

Sl. No	Sub Code	Subject Name	IA Test-I 12/9/19 - 14/9/19				IA Test-II				IA Test-III				Final Marks
			Attendance			Marks	Attendance			Mark s	Attendance			Marks	
			CT	CA	%		CT	CA	%		CT	CA	%		
						30				30				30	40
1	18MAT31	Maths - III	18	14	77	16	30	20	67	15	52	35	68	30	31
2	18EE32	ECA	21	15	71	21	37	28	76	24	62	47	76	24	33
3	18EE33	T & G	18	14	77	21	30	23	77	15	55	37	68	13	27
4	18EE34	AEC	20	15	75	19	30	23	77	16	50	38	76	25	30
5	18EE35	DSD	16	11	69	24	34	26	76	21	66	50	76	15	30
6	18EE36	EEM	16	11	69	19	35	32	91	23	51	37	73	20	31
7	18EEL37	Machines Lab-I	7	5	71	—	9	8	89	—	12	11	92	—	37
8	18EEL38	Electronics Lab	7	5	71	—	9	7	78	—	12	10	83	—	32

CT=No. of Classes Taken      CA=No. of Classes Attended

Overall % of attendance in III semester: 74 %

Signature of the Student

Signature of the Mentor

Signature of the HOD



Counselling	Date/Time	Identified Shortfalls in the Academic Performance	Student Remarks	Signature	
				Student	Mentor
Counselling After 1 <sup>st</sup> IA Test	20/9/19	Irregular to classes; work hard to improve the score	Yes will score. Erud	High	Ln
Counselling After 2 <sup>nd</sup> IA Test	25/10/19	Irregular; should improve in Math, T&A, AEC	Thank You, Will improve the score.	High	Ln
Counselling After 3 <sup>rd</sup> IA Test	29/11/19	Poor attendance; should study T&D and DSD	Thank You, will improve the score	High	Ln

Signature of the Student

Signature of the Mentor

Signature of the HOD



### III SEMESTER UNIVERSITY RESULTS

Arrears (if any) : 1

SGPA/%: —

CLASS OBTAINED : FAIL

Sub Code	18MAT31			18EE32			18EE33			18EE34			18EE35			18EE36			18EEL37			18EEL38		
SubName	Eng. Maths III			Electric Circuit Analysis			Transformer & Generators			Analog Electronics Circuits			Digital System Design			Measurements			Machines Lab			Electronics Lab		
Month & Year	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T
January 2020	35	29	64	33	14	47	27	23	50	30	23	53	32	30	62	34	28	59	37	54	91	32	53	85

IA=Final IA Marks

Ext.= External Exam Marks

T=Total(IA+Ext.)

511/800

### Counselling after University Results

Date of Counselling	Time	Mentor Notes	Student Remarks
20/4/2020	3.15 to 3.30 pm	Hard work required for problematic subjects	will pass in all subjects

*Signature*  
Signature of the Student

*Signature*  
Signature of the Mentor

*Signature*  
Signature of the HOD





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## UNDERTAKING BY STUDENT

I, B. R. M. Thiruganeshwari, USN 10X18EE009, studying B.E in III<sup>rd</sup> semester, am aware that I have attendance shortage as on today and the statutory requirement for appearing VTU exam is 85%.

I assure that I shall be regular to the classes from now onwards. In case, I am detained due to shortage of attendance, I am solely and wholly responsible for detention.

Date: 10/7/2019

Hirigse  
Signature of the Student

## UNDERTAKING BY PARENT

I am aware that my ward \_\_\_\_\_, USN studying B.E in \_\_\_\_\_ semester is having attendance shortage as of today (Date: \_\_\_\_\_) and the statutory requirement for appearing VTU exam is 85%.

I assure that my ward will be regular to the classes from now onwards. In case, He/She is detained due to shortage of attendance, my ward will be solely and wholly responsible for detention.

Date: \_\_\_\_\_

Name of the Parent: \_\_\_\_\_

Relationship: \_\_\_\_\_

Mobile No: \_\_\_\_\_

Signature of the Parent/Guardian \_\_\_\_\_



# IV SEMESTER

## Attendance & Performance in Internal Assessment Test

Max Marks:

Sl. No	Sub Code	Subject Name	IA Test-I				IA Test-II				IA Test-III				Final Marks
			Attendance			Marks	Attendance			Mark s	Attendance			Marks	
			CT	CA	%		CT	CA	%		CT	CA	%		
						(30)				(30)				(30)	(40)
1	18MAT41	Probability and Statistical methods	18	14	77	28	30	25	83	30	52	47	91	30	39
2	18EE42	Power Generation & Economics	21	15	71	24	37	31	84	30	62	55	89	30	38
3	18EE43	Transmission & Distribution	18	14	77	29	30	26	87	30	55	51	93	30	40
4	18EE44	Electric motors	20	15	75	22	30	24	80	30	50	43	86	30	37
5	18EE45	Field Theory	20	15	75	36	34	28	82	39	64	57	89	32	37
6	18EE46	Opamps & linear ICs	18	14	77	37	35	31	89	40	51	46	90	38	39
7	18EEL47	Machines Lab-2	6	6	100	-	9	9	100	-	11	11	100	-	
8	18EEL48	Opamp & linear ICs Lab.	6	6	100	-	9	9	100	-	11	11	100	-	

CT=No. of Classes Taken      CA=No. of Classes Attended

CT=No. of Classes Taken

CA=No. of Classes Attended

Overall % of attendance in IV semester: 92.25 %

Signature of the Student

Signature of the Mentor

Signature of the HOD



Counselling	Date/Time	Identified Shortfalls in the Academic Performance	Student Remarks	Signature	
				Student	Mentor
Counselling After 1 <sup>st</sup> IA Test	20/4/20	Irregular to classes; should concentrate more.	will attend regularly.	Hrigue	ph
Counselling After 2 <sup>nd</sup> IA Test	28/5/20	Regular for online classes	-	Hrigue	ph
Counselling After 3 <sup>rd</sup> IA Test	20/6/20	Regular for online classes, should concentrate on problematic subjects.	Problematic subjects difficult to follow in online classes.	Hrigue	ph

Signature of the Student

Signature of the Mentor

Signature of the HOD



# IV SEMESTER UNIVERSITY RESULTS

Arrears (if any) : NIL

SGPA/%: 77.88 %

CLASS OBTAINED : FCD

Sub Code	18MAT41			18EE42			18EE43			18EE44			18EE45			18EE46			18EEL47			18EEL48		
SubName	Prob. & Statistical methods			Power Gen. & Economics			Transmission & Distribution			Electrical motors			Field theory			opamp & Linear ICs			Machines Lab-2			op amp Lab.		
Month & Year	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T	IA	Ext	T
September 2020	50	28	78	50	28	78	50	28	78	49	28	77	50	28	78	50	28	78	50	28	78	50	28	78

IA=Final IA Marks

Ext.= External Exam Marks

T=Total (IA+Ext.)

623/800

## Counselling after University Results

Date of Counselling	Time	Mentor Notes	Student Remarks
25/10/20	10:15 to 10:30 pm	Should work hard in problematic subjects	ok.

Signature of the Student

Signature of the Mentor

Signature of the HOD



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Affiliated to VTU, Belagavi

## UNDERTAKING BY STUDENT

I, B. R. M. Abhishek, USN 11111111, studying B.E in IT<sup>th</sup> semester, am aware that I have an attendance shortage as on today and the statutory requirement for appearing VTU exam is 85%.

I assure that I shall be regular to the classes from now onwards. In case, I am detained due to shortage of attendance, I am solely and wholly responsible for detention.

Signature of the Student

Date:

05/2/2020

## UNDERTAKING BY PARENT

I am aware that my ward \_\_\_\_\_, USN studying B.E in \_\_\_\_\_ semester is having attendance shortage as of today (Date: \_\_\_\_\_) and the statutory requirement for appearing VTU exam is 85%.

I assure that my ward will be regular to the classes from now onwards. In case, He/She is detained due to shortage of attendance, my ward will be solely and wholly responsible for detention.

Date:

Name of the Parent:

Relationship:

Mobile No:

Signature of the Parent/Guardian

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PRINCIPAL  
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